



(51) International Patent Classification:
H01L 21/28 (2006.01) *H01L 21/762* (2006.01)

(21) International Application Number:
PCT/US2010/024302

(22) International Filing Date:
16 February 2010 (16.02.2010)

(25) Filing Language: English

(26) Publication Language: English

(30) Priority Data:
61/152,899 16 February 2009 (16.02.2009) US

(71) Applicant (for all designated States except US): **THE BOARD OF TRUSTEES OF THE LELAND STANFORD JUNIOR UNIVERSITY** [US/US]; 1705 El Camino Real, Palo Alto, CA 94306 (US).

(72) Inventors; and

(75) Inventors/Applicants (for US only): **JAIN, Jinendra, Raja** [US/US]; 334 Olmsted Road, Apt. 106, Stanford, CA 94305 (US). **HOWE, Roger, T.** [US/US]; 420 Via Palou, Stanford, CA 94305 (US).

(74) Agents: **DAVIS, Paul** et al.; Goodwin Procter LLP, 135 Commonwealth Drive, Menlo Park, CA 94025 (US).

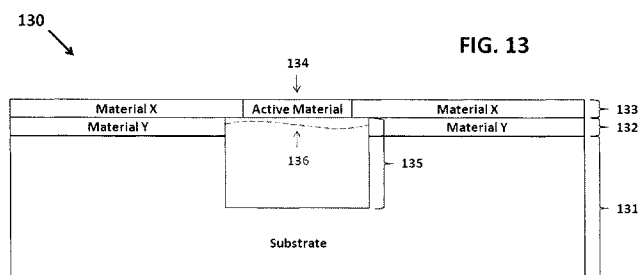
(81) Designated States (unless otherwise indicated, for every kind of national protection available): AE, AG, AL, AM, AO, AT, AU, AZ, BA, BB, BG, BH, BR, BW, BY, BZ, CA, CH, CL, CN, CO, CR, CU, CZ, DE, DK, DM, DO, DZ, EC, EE, EG, ES, FI, GB, GD, GE, GH, GM, GT, HN, HR, HU, ID, IL, IN, IS, JP, KE, KG, KM, KN, KP, KR, KZ, LA, LC, LK, LR, LS, LT, LU, LY, MA, MD, ME, MG, MK, MN, MW, MX, MY, MZ, NA, NG, NI, NO, NZ, OM, PE, PG, PH, PL, PT, RO, RS, RU, SC, SD, SE, SG, SK, SL, SM, ST, SV, SY, TH, TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, ZA, ZM, ZW.

(84) Designated States (unless otherwise indicated, for every kind of regional protection available): ARIPO (BW, GH, GM, KE, LS, MW, MZ, NA, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HR, HU, IE, IS, IT, LT, LU, LV, MC, MK, MT, NL, NO, PL, PT, RO, SE, SI, SK, SM, TR), OAPI (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).

Published:

— with international search report (Art. 21(3))

(54) Title: STRAINED SEMICONDUCTOR MATERIALS, DEVICES AND METHODS THEREFORE



(57) Abstract: Various applications are directed to a material stack having a strained active material therein. In connection with an embodiment, an active material (e.g. a semiconductor material) is at least initially and partially released from and suspended over a substrate, strained, and held in place. The release and suspension facilitates the application of strain to the semiconductor material.

STRAINED SEMICONDUCTOR MATERIALS, DEVICES AND METHODS THEREFORE

FIELD OF THE INVENTION

5 The present invention relates generally to semiconductors, and more particularly to semiconductor devices involving strained semiconductor materials.

BACKGROUND OF THE INVENTION

10 A variety of electronic and optoelectronic fields and related devices use semiconductor materials to suit a variety of purposes. In many implementations, the properties of various materials used to make these devices are selected or otherwise tailored to suit specific applications.

15 One of many representative semiconductor fields that have been of significant interest in recent times is the field of optoelectronics. The field of optoelectronics includes those materials, structures, devices, circuits, and systems that have properties appropriate for facilitating optical-electrical energy and signal conversion, transmission, modulation, and detection. Most optoelectronic devices in production today use III-V materials to achieve high performance. However, in light of a number of drawbacks concerning III-Vs, including process/fabrication complexity, high material costs, and incompatibility with silicon (Si), among others, some
20 researchers have begun exploring alternatives to these traditional approaches to optoelectronics problems.

25 Photodetectors, for example, are optoelectronic devices that convert optical signals into electrical signals. At a general level, a photodetector is at least partially comprised of a light-absorption medium that is in electrical contact with a set of electrodes. Light energy is absorbed in the medium by excitation of electrons from valence bands into conduction bands, while current is generated via the transport of these excited charge carriers to the electrodes and through an external circuit. In the case of light emission, light-emitting diodes (LEDs) and lasers are the optoelectronic counterparts to photodetectors, converting electrical energy into optical energy. At a
30 general level, these light emitting devices are also at least partially comprised of an optically active medium, which may include a multiplicity of several materials with different characteristics, in electrical contact with sets of electrodes. In these types of

devices, electrical energy is passed through the optical medium by the application of a potential difference via the electrodes. While current flows through the medium, some of the associated charge carriers recombine with each other as electrons drop from the conduction bands back to the valence bands. For radiative recombination events, the energy associated with these transitions is emitted in the form of light via photons. As a third category of optoelectronic devices, modulators modify light, converting electrical signals into optical signals. Generally, these types of devices are also at least partially comprised of an optically active medium, which may include a multiplicity of several materials with different characteristics, in electrical contact with sets of electrodes. The application of a potential difference across the optical medium via the electrodes changes its optical properties, modulating the properties of a beam of light passing through it.

Photodetectors, lasers, and modulators are some of the key components in optical communications systems and often operate at a wavelength range that is inclusive of about 1300nm-1600nm (*i.e.* they interact with light energy relatively efficiently at these wavelengths for these particular applications). For telecommunications, certain standards are defined around 1550nm, where the 1528-1560nm range is referred to as the “C-Band” and the 1561-1620nm range is known as the “L-Band.”

Many commercially available optoelectronic devices, such as the photodetectors, LEDs, lasers, and modulators described above, use type III-V materials such as GaAs, InGaAs, and GaN, which have the subset of disadvantages mentioned previously. For the particular examples here of photodetection, emission, and modulation, germanium (Ge) has attractive properties and is a promising silicon-compatible alternative as an optically active medium.

Unlike the III-V materials and their associated drawbacks, germanium does not undermine the performance of other devices that are built on a shared silicon-compatible platform. Therefore, silicon-compatible substrates can be used in a system that integrates other silicon-compatible electronic and/or optoelectronic devices and germanium-based optoelectronics, for example. Moreover, germanium fabrication and processing technologies are very similar to those used in traditional silicon manufacturing, reducing fabrication costs and complexity significantly compared to the III-Vs.

However, while bulk germanium may represent an attractive alternative to

III-V materials for applications at the lower wavelength range, it suffers from limitations at wavelengths larger than about 1500nm. In particular, bulk germanium has an absorption coefficient at 1550nm that is about 1/20th the absorption coefficients of some III-V materials (*e.g.* InGaAs), requiring a relatively thick
5 germanium layer for comparable photodetection at this wavelength and resulting in low operating speeds. In terms of light emission, germanium's optical output is especially weak due to several competing phenomena. This less-than-optimal optoelectronic performance is directly related to the band structure of bulk germanium.

10 For the case of photodetection, when light is absorbed by a material, its energy is used to lift electrons above an energetic bandgap between the valence and conduction bands to higher-energy states. Thus, to first-order, if the incident light energy does not exceed the energy of the bandgap, the light cannot be absorbed and it passes through the medium undetected. In germanium, there are two
15 particularly relevant bandgaps: the indirect L and the direct gamma. The indirect L bandgap is about 0.667eV in energy, while the direct gamma bandgap represents an energy barrier of about 0.8eV. In terms of light wavelength, these energies correspond to about 1860nm and about 1550nm, respectively.

Unfortunately, germanium cannot efficiently absorb light energy at the
20 band edges for several reasons. Absorption leading to excitation above the indirect bandgap requires the co-action of a phonon-related momentum transfer along with the photon-related energy gain. The simultaneous occurrence of these two events at the right energy and momentum is relatively rare, resulting in small absorption coefficients for indirect gap transitions. For direct bandgap transitions at the
25 germanium gamma point, the low density of available charge states near the conduction band edge limits the number of carriers that can be excited just above the direct gap. The density of such states increases beyond the band edge, but transitions to these states require higher-energy (smaller wavelength) photons. Photon absorptions and carrier excitations occur preferentially at the direct bandgap
30 due to momentum conservation. Phonon-assisted momentum transfers are not necessary for such transitions.

In terms of light emission, the germanium band structure poses a more fundamental problem. The energy offset between the L and gamma bands and their relative difference in densities of states lead to preferential carrier occupation of the

L valley and significantly stronger phonon-assisted non-radiative (rather than radiative) recombination. As a result, charge carriers that are injected into bulk germanium (e.g. via an applied potential difference) occupy the lower-energy L-valley states and can drop down to the valence band primarily only by recombining non-radiatively. Thus, it is very difficult to make bulk germanium emit light without injecting an inordinately large amount of charge carriers. Such high levels of carrier injection are impractical, requiring very high applied voltages and/or very low operating temperatures.

Applying different types of tensile strain to germanium alters its band structure, in part by reducing the direct bandgap relative to the indirect bandgap, thereby increasing the relative density of available states in the direct gamma valley and improving photon absorption and emission. In particular, reducing the direct bandgap via strain (e.g. biaxial tensile strain) can expand the useful range of light absorption and emission achievable by germanium-based photodetectors and emitters to include the L and C telecommunication bands, as well as the longer wavelengths. For instance, applying around 0.2% biaxial tensile strain to germanium increases its absorption coefficient at 1550nm by about 7.5 times, compared to unstrained germanium.

However, approaches to applying tensile strain to germanium in a silicon-compatible manner have fallen far short of the levels desired, involved material configurations that introduce drawbacks for final device performance and capabilities, and/or have involved complex fabrication processes that require particularly tight controls. As a result of these complications and relative to telecommunications, for example, a large portion of the optical communications spectrum has been left relatively unsupported by germanium.

These and other matters have presented challenges to the design, manufacture and implementation of semiconductor devices, and in particular, of silicon-compatible devices such as those used in optoelectronics.

SUMMARY OF THE INVENTION

An object of the present invention is to provide new and improved semiconductor devices and their methods of manufacture.

A further object of the present invention is to provide new and improved

semiconductor devices such as those used in electronics and/or optoelectronics and their methods of manufacture.

A further object of the present invention is to provide new and improved silicon-compatible semiconductor devices and their methods of manufacture.

5 A further object of the present invention is to provide new and improved silicon-compatible semiconductor devices such as those used in electronics and/or optoelectronics and their methods of manufacture.

10 A further object of the present invention is to provide semiconductor devices that include materials with highly-tunable strains and their methods of manufacture.

A further object of the present invention is to provide semiconductor devices that include materials with highly-tunable strains and are used in electronics and/or optoelectronics and their methods of manufacture.

15 A further object of the present invention is to provide silicon-compatible semiconductor devices that include materials with highly-tunable strains and their methods of manufacture.

A further object of the present invention is to provide silicon-compatible semiconductor devices that include materials with highly-tunable strains and are used in electronics and/or optoelectronics and their methods of manufacture.

20 A further object of the present invention is to provide semiconductor devices with engineered electronic and/or optoelectronic characteristics and their methods of manufacture.

25 A further object of the present invention is to provide silicon-compatible semiconductor devices with engineered electronic and/or optoelectronic characteristics and their methods of manufacture.

30 These and other objects of the present invention are achieved in a semiconductor device that includes a substrate, an active material, materials configured and arranged to induce a strain in the active material, materials configured and arranged to mitigate relaxation of the strain induced in the active material, and a support structure that suspends the active material over a portion of the substrate.

The present invention is exemplified in a number of implementations and applications, only some of which are summarized below.

According to one aspect, the present invention is directed to an active

material including a semiconductor material, such as germanium, that is partially released from at least part of the underlying materials and/or substrate and strained by an adjacent material or related process. The release is used to set or otherwise control the application of strain, such as by controlling the active material's amenability to strain and to maintaining the strain.

According to another example embodiment, a semiconductor device includes a substrate, a material stack, and a support structure to support the released material stack over a portion of the substrate. The material stack includes a first material over the substrate, an active material on the first material, and a second material on the active material. At least one of the first and second materials is configured and arranged to induce a strain in the active material, and at least one of the first and second materials is configured and arranged to mitigate relaxation of the strain induced in the active material.

Other embodiments are exemplified in the figures, including those in the Appendix, which forms part of this patent document.

The above summary of the present invention is not intended to describe each illustrated embodiment or every other possible implementation of the present invention. The figures and detailed description that follow more particularly exemplify only certain embodiments.

BRIEF DESCRIPTION OF THE DRAWINGS

The present invention may be more completely understood in consideration of the detailed descriptions of various example embodiments of the invention that follow in connection with the accompanying drawings, in which:

FIG. 1 depicts a cross-section of an active material-based structure having a strained active material vertically adjacent to an overlying material and an underlying substrate, a portion of which is removed to a depth within the underlying substrate under an area of the active material, according to an example embodiment of the present invention;

FIG. 2 depicts a cross-section of an active material-based structure having a strained active material vertically adjacent to an overlying material and an underlying substrate, a portion of which is removed to the bottom of the underlying substrate under an area of the active material, according to another example embodiment of the present invention;

FIG. 3 depicts a cross-section of an active material-based structure having a strained active material horizontally adjacent to other materials and vertically adjacent to an underlying substrate, a portion of which is removed to a depth within the underlying substrate under an area of the active material, according to another example embodiment of the present invention;

FIG. 4 depicts a cross-section of an active material-based structure having a strained active material horizontally adjacent to other materials and vertically adjacent to an underlying substrate, a portion of which is removed to the bottom of the underlying substrate under an area of the active material, according to another example embodiment of the present invention;

FIG. 5 depicts a cross-section of an active material-based structure having a strained active material vertically adjacent to an overlying material and an underlying material over an underlying substrate, a portion of which is removed to a depth within the underlying substrate under an area of the active material, according to another example embodiment of the present invention;

FIG. 6 depicts a cross-section of an active material-based structure having a strained active material vertically adjacent to an overlying material and an underlying material over an underlying substrate, a portion of which is removed to the bottom of the underlying substrate under an area of the active material, according to another example embodiment of the present invention;

FIG. 7 depicts a cross-section of an active material-based structure having a strained active material horizontally adjacent to other materials and vertically adjacent to an underlying material over an underlying substrate, a portion of which is removed to a depth within the underlying substrate under an area of the active material, according to another example embodiment of the present invention;

FIG. 8 depicts a cross-section of an active material-based structure having a strained active material horizontally adjacent to other materials and vertically adjacent to an underlying material over an underlying substrate, a portion of which is removed to the bottom of the underlying substrate under an area of the active material, according to another example embodiment of the present invention;

FIG. 9 depicts a cross-section of an active material-based structure having a strained active material vertically adjacent to an overlying material and an underlying material over an underlying substrate, where a portion of the underlying material is removed under an area of the active material, according to another

example embodiment of the present invention;

FIG. 10 depicts a cross-section of an active material-based structure having a strained active material vertically adjacent to an overlying material and an underlying material over an underlying substrate, where a portion of the underlying material and underlying substrate is removed to a depth within the underlying substrate under an area of the active material, according to another example embodiment of the present invention;

FIG. 11 depicts a cross-section of an active material-based structure having a strained active material vertically adjacent to an overlying material and an underlying material over an underlying substrate, where a portion of the underlying material and underlying substrate is removed to the bottom of the underlying substrate under an area of the active material, according to another example embodiment of the present invention;

FIG. 12 depicts a cross-section of an active material-based structure having a strained active material horizontally adjacent to other materials and vertically adjacent to an underlying material over an underlying substrate, where a portion of the underlying material is removed under an area of the active material, according to another example embodiment of the present invention;

FIG. 13 depicts a cross-section of an active material-based structure having a strained active material horizontally adjacent to other materials and vertically adjacent to an underlying material over an underlying substrate, where a portion of the underlying material and underlying substrate is removed to a depth within the underlying substrate under an area of the active material, according to another example embodiment of the present invention; and

FIG. 14 depicts a cross-section of an active material-based structure having a strained active material horizontally adjacent to other materials and vertically adjacent to an underlying material over an underlying substrate, where a portion of the underlying material and underlying substrate is removed to the bottom of the underlying substrate under an area of the active material, according to another example embodiment of the present invention.

While the present invention is amenable to various modifications and alternative forms, specifics thereof have been shown by way of example in the drawings and will be described in detail. It should be understood, however, that the intention is not necessarily to limit the invention to the particular example

embodiments described and claimed. On the contrary, the intention is to cover all modifications, equivalents, and alternatives falling within the spirit and scope of the invention.

DETAILED DESCRIPTION OF THE INVENTION AND DRAWINGS

The present invention is believed to be useful for a variety of different applications involving semiconductors, and the invention has been found to be particularly suited for semiconductor devices having strained active materials. While the present invention is not necessarily limited to such applications, various aspects of the invention may be appreciated through a discussion of several examples within this context.

The present invention can be utilized with a variety of different active materials with strained or straining active material-based layers and active materials that need not be in a layer structure, and further in connection with electronic and optoelectronic devices. The active material can actually include of a number of different materials grown on top of each other (e.g. several epilayers) or other materials arranged horizontally but in physical contact, or any of a variety of other material types, number, and configuration. By way of illustration, and without limitation, for a particular example laser configuration, including but not limited to, edge-emitter, VCSEL, and the like, SiGe, SiGeSn, or SiGeC quantum wells, or even the traditional III-V materials, can be deposited, and then the entire material stack can be strained after all the materials are formed.

As a non-limiting example, the active materials can be selected from one or more of, materials and film types including but not limited to, Si, Ge, SiGe, SiGeSn, SiGeC, III-V materials, graphene, nanotubes, nanowires, metals, and others. Applying strain to a material alters its band structure and electronic/optoelectronic properties. This opens up an entirely new space for devices across a variety of applications, not merely silicon-compatible optoelectronics.

However, these embodiments are exemplary and may be implemented in connection with different numbers and types of materials and with different types of devices. For instance, a silicon-based material or other semiconductor material may be used in place of the discussed active material. The materials, layers, and other structures discussed as implemented with optoelectronic devices may be implemented with a variety of other devices, such as transistors, thyristors, memory

devices and others.

According to an example embodiment, an active material is used as part of an optoelectronic structure, with another material that strains the active material under conditions involving at least a partial suspension of the active material. The strained active material is held in a strained state. This approach is amenable to implementation with, for example, optical photodetectors, LEDs, lasers, modulators, and photonic crystals, as well as a wide variety of other devices and systems (including improvements to current ones).

In many implementations, the active material is suspended in a manner that avoids and/or removes a force-energy balance between a suspended portion of the active material and an underlying material. The material used to strain the active material has an internal stress that is transferred to the suspended active material due to a modified force-energy balance therebetween, altering the active material's band structure to adjust its electronic and/or optoelectronic properties. This stress transfer is particularly effective due to the suspended nature of at least part of the active material, in that the strain transfer and concomitant band structure alteration is not inhibited by physical contact between the suspended portion of the active material and at least one of the underlying materials.

The composition, dimensions (e.g. thickness), internal strain state, shape, or other geometrical arrangement of the suspended active material, the materials applying stress and/or other materials underlying or adjacent to the suspended material are used to set strain characteristics of the active material to suit particular applications. For instance, relatively large changes in atomic spacing can be achieved with a relatively thin active material (*i.e.* to induce high stress and/or strain).

In some implementations, a suspended region of the active material is sandwiched between two other materials to form a material stack that is supported at its ends and/or edges by an underlying substrate. The materials sandwiching the active material respectively apply strain to the active material, altering its band structure.

In some embodiments, the active material is formed on a substrate and subsequently suspended by removing a portion of the underlying substrate or materials, yet leaving some of the underlying materials or substrate in contact with at least part of the suspended active material to limit the amount of stress or strain applicable thereto, and to keep the structure intact and connected to the substrate.

One such implementation involves using an active material-on-insulator (e.g. germanium-on-insulator (GOI)) stack, in which an active material layer is formed on an insulator layer, and in which a portion of the material stack is suspended. In one of several process variations, another material layer, such as an insulator, is formed on top of the active material-on-insulator stack to induce strain in the active material layer. A region of an underlying substrate (e.g. silicon) is removed up to the bottom insulator to release the material stack, from the backside and/or from the topside in a certain pattern and using certain chemistries to etch under the region of interest. Removal of the substrate underneath the active material stack results in a thinner total material stack in the region of interest, to balance internal stresses of the insulators by much larger stresses in the active material than could have been achieved, absent the suspension (*i.e.* the active material will experience significant strain and a considerable alteration of its band structure).

In certain implementations, a portion of the substrate underlying the active material-on-insulator stack is left intact below the suspended material stack to set characteristics of the device. In other implementations, a portion of the insulator underlying the active material is removed as well, to similarly set characteristics of the device and of the active material. These approaches are readily implemented for a variety of different applications, to set or otherwise tune characteristics of the active material related to stress or strain therein and/or to tune or set device characteristics.

Turning now to the figures, **FIG. 1** depicts a cross-section of an active material-based structure **010** having a strained active material **012** vertically adjacent to an overlying material **013** and an underlying substrate **011**, a portion of which **014** is removed to a depth within the underlying substrate **011** under an area of the active material **012**, according to an example embodiment of the present invention.

To facilitate the application of strain to the active material **012**, a portion of the underlying substrate **011** is removed to expose a region **014**, over which the active material **012** is suspended. As discussed above, the amount of the underlying substrate **011** removed below the active material **012** is based upon desired characteristics of the active material **012** and device/application considerations. Accordingly, dashed line **015** defines a region of the underlying substrate **011** that is left intact below the active material **012**, as representing an exemplary approach to removing less than all of the substrate **011** underlying the suspended portion of the

active material **012**. Further, the amount of the underlying substrate **011** removed below the active material **012** to a depth within the underlying substrate **011** may also be determined by other desired material and device characteristics, which may include structural integrity of the remaining underlying substrate **011**, device
5 integration schemes, and others.

The overlying material **013** may include one or more of a variety of materials, which can be implemented to strain the active material **012** and/or to hold the active material **012** in a strained state. In some implementations, the overlying material **013** may be used to strain the active material **012**, with the underlying
10 substrate **011** used to hold the active material **012** in place. In other implementations, the underlying substrate **011** may be used to strain the active material **012**, with the overlying material **013** used to hold the active material **012** in place. In still other implementations, both the overlying material **013** and the underlying substrate **011** may be used to both strain the active material **012** and hold
15 the active material **012** in place. In still other implementations, other processing steps, such as thermal treatments, mechanical bending, and others, may be used to strain the active material **012**, with the overlying material **013** and/or the underlying substrate **011** used to hold the active material **012** in place.

The specific fabrication process for the structure **010** can be carried out in
20 one or more of a variety of manners, depending upon the desired material and device characteristics. In some embodiments, an initial active material-on-substrate stack (represented by **012** and **011**) can be released from the underlying substrate **011** (e.g. as shown at region **014** with the region represented by dashed line **015** intact), followed by the formation of an overlying stressed material (represented by
25 **013**). In other embodiments, an overlying stressed material (represented by **013**) is formed first, with the material stack released from the underlying substrate **011** afterwards. Different approaches to the final strained material stack may be useful for different embodiments.

In other example embodiments, the structure **010** is integrated with
30 electronics and/or optoelectronics to facilitate the fabrication of electronic and/or optoelectronic devices, circuits, and systems in any of a variety of integration schemes. Optoelectronic devices with which the structure **010** may be used include, for example and without limitation, photodetectors, telecommunications devices, modulators, light-emitting diodes (LEDs), on-chip optical interconnects, lasers,

quantum well modulators, waveguide lasers/modulators, photonic crystals and active material-based optoelectronics operating in the L and C telecommunications bands and at other wavelengths.

Other devices with which the structure **010** may be used in a variety of embodiments include devices that do not necessarily involve optoelectronics, such as transistor devices, memory devices, and others, with the application of strain used to set various properties of the active material **012**. For instance, strain may be used to set charge carrier mobility, ON current, operating speed, and other electronic characteristics of transistors that include strained active materials (represented by **012**).

Additionally, in some embodiments, the area of the removed portion **014** of the underlying substrate **011** is left as-is (*i.e.* empty as free space) after the portion **014** is removed. In other embodiments, this area is refilled with another material to satisfy any of a variety of desired material, device, circuit, and system characteristics.

FIG. 2 depicts a cross-section of an active material-based structure **020**, similar to that shown in **FIG. 1**, having a strained active material **022** vertically adjacent to an overlying material **023** and an underlying substrate **021**, a portion of which **024** is removed to the bottom of the underlying substrate **021** under an area of the active material **022**, according to another example embodiment of the present invention.

As discussed above, to facilitate the application of strain to the active material **022**, a portion of the underlying substrate **021** is removed to expose a region **024**, over which the active material **022** is suspended. The amount of the underlying substrate **021** removed below the active material **022** is based upon desired characteristics of the active material **022** and device/application considerations. Accordingly, dashed line **025** defines a region of the underlying substrate **021** that is left intact below the active material **022**, as representing an exemplary approach to removing less than all of the substrate **021** underlying the suspended portion of the active material **022**.

As discussed above, in some embodiments, the structure **020** is integrated with electronics and/or optoelectronics to facilitate the fabrication of electronic and/or optoelectronic devices, circuits, and systems in any of a variety of integration schemes. In the structure **020**, removal of a portion **024** of the underlying substrate

021 to the bottom of the underlying substrate **021** also facilitates integration with backside electronics and/or optoelectronics. Backside electronic and/or optoelectronic access to the active material **022** is made possible via the backside at **024** to permit different device, circuit, and system integration schemes. In some
5 embodiments, the structure **020** may be used for applications involving wafer stacking (e.g. 3D integrated circuits), where electronic and /or optoelectronic access to the backside of the active material **022** is desired.

Additionally, as discussed above, in some embodiments, the area of the removed portion **024** of the underlying substrate **021** is left as-is (*i.e.* empty as free
10 space) after the portion **024** is removed. In other embodiments, this area is refilled with another material to satisfy any of a variety of desired material, device, circuit, and system characteristics.

FIG. 3 depicts a cross-section of an active material-based structure **030** having a strained active material **033** horizontally adjacent to other materials **032** and
15 vertically adjacent to an underlying substrate **031**, a portion of which **034** is removed to a depth within the underlying substrate **031** under an area of the active material **033**, according to another example embodiment of the present invention.

As discussed above, to facilitate the application of strain to the active material **033**, a portion of the underlying substrate **031** is removed to expose a
20 region **034**, over which the active material **033** is suspended. The amount of the underlying substrate **031** removed below the active material **033** is based upon desired characteristics of the active material **033** and device/application considerations. Accordingly, dashed line **035** defines a region of the underlying substrate **031** that is left intact below the active material **033**, as representing an
25 exemplary approach to removing less than all of the substrate **031** underlying the suspended portion of the active material **033**. Further, the amount of the underlying substrate **031** removed below the active material **033** to a depth within the underlying substrate **031** may also be determined by other desired material and device characteristics, which may include structural integrity of the remaining underlying
30 substrate **031**, device integration schemes, and others.

The horizontally adjacent materials **032** may include one or more of a variety of materials, which can be implemented to strain the active material **033** and/or to hold the active material **033** in a strained state. In some implementations, the horizontally adjacent materials **032** may be used to strain the active material **033**,

with the underlying substrate **031** used to hold the active material **033** in place. In other implementations, the underlying substrate **031** may be used to strain the active material **033**, with the horizontally adjacent materials **032** used to hold the active material **033** in place. In still other implementations, both the horizontally adjacent materials **032** and the underlying substrate **031** may be used to both strain the active material **033** and hold the active material **033** in place. In still other implementations, other processing steps, such as thermal treatments, mechanical bending, and others, may be used to strain the active material **033**, with the horizontally adjacent materials **032** and/or the underlying substrate **031** used to hold the active material **033** in place.

The specific fabrication process for the structure **030** can be carried out in one or more of a variety of manners, depending upon the desired material and device characteristics. In some embodiments, an initial active material-on-substrate stack (represented by **033** and **031**) can be partially released from the underlying substrate **031** (e.g. as shown at region **034** with the region represented by dashed line **035** intact), followed by the formation of horizontally adjacent stressed materials (represented by **032**). In other embodiments, horizontally adjacent stressed materials (represented by **032**) are formed first, with the material stack released from the underlying substrate **031** afterwards. Different approaches to the final strained material stack may be useful for different embodiments.

Additionally, as discussed above, in some embodiments, the area of the removed portion **034** of the underlying substrate **031** is left as-is (*i.e.* empty as free space) after the portion **034** is removed. In other embodiments, this area is refilled with another material to satisfy any of a variety of desired material, device, circuit, and system characteristics.

FIG. 4 depicts a cross-section of an active material-based structure **040**, similar to that shown in **FIG. 3**, having a strained active material **043** horizontally adjacent to other materials **042** and vertically adjacent to an underlying substrate **041**, a portion of which **044** is removed to the bottom of the underlying substrate **041** under an area of the active material **043**, according to another example embodiment of the present invention.

As discussed above, to facilitate the application of strain to the active material **043**, a portion of the underlying substrate **041** is removed to expose a region **044**, over which the active material **043** is suspended. The amount of the

underlying substrate **041** removed below the active material **043** is based upon desired characteristics of the active material **043** and device/application considerations. Accordingly, dashed line **045** defines a region of the underlying substrate **041** that is left intact below the active material **043**, as representing an exemplary approach to removing less than all of the substrate **041** underlying the suspended portion of the active material **043**.

Additionally, as discussed above, in some embodiments, the area of the removed portion **044** of the underlying substrate **041** is left as-is (*i.e.* empty as free space) after the portion **044** is removed. In other embodiments, this area is refilled with another material to satisfy any of a variety of desired material, device, circuit, and system characteristics.

FIG. 5 depicts a cross-section of an active material-based structure **050** having a strained active material **053** vertically adjacent to an overlying material **054** and an underlying material **052** over an underlying substrate **051**, a portion of which **055** is removed to a depth within the underlying substrate **051** under an area of the active material **053**, according to another example embodiment of the present invention.

As discussed above, to facilitate the application of strain to the active material **053**, a portion of the underlying substrate **051** is removed to expose a region **055**, over which the active material **053** is suspended. The amount of the underlying substrate **051** removed below the active material **053** is based upon desired characteristics of the active material **053** and device/application considerations. Accordingly, dashed line **056** defines a region of the underlying substrate **051** that is left intact below the underlying material **052**, as representing an exemplary approach to removing less than all of the substrate **051** underlying the suspended portion of the active material **053**. Further, the amount of the underlying substrate **051** removed below the active material **053** to a depth within the underlying substrate **051** may also be determined by other desired material and device characteristics, which may include structural integrity of the remaining underlying substrate **051**, device integration schemes, and others.

The respective materials **054** and **052** may include one or more of a variety of materials, which can be implemented to strain the active material **053** and/or to hold the active material **053** in a strained state. In some implementations, the overlying material **054** may be used to strain the active material **053**, with the

underlying material **052** used to hold the active material **053** in place. In other implementations, the underlying material **052** may be used to strain the active material **053**, with the overlying material **054** used to hold the active material **053** in place. In still other implementations, both the overlying material **054** and the
5 underlying material **052** may be used to both strain the active material **053** and hold the active material **053** in place. In still other implementations, other processing steps, such as thermal treatments, mechanical bending, and others, may be used to strain the active material **053**, with the overlying material **054** and/or the underlying material **052** used to hold the active material **053** in place.

10 The specific fabrication process for the structure **050** can be carried out in one or more of a variety of manners, depending upon the desired material and device characteristics. In some embodiments, an initial active material-on-insulator stack (represented by **053**, **052**, and **051**) can be released from the underlying substrate **051** (e.g. as shown at region **055**), followed by the formation of an
15 overlying stressed material (represented by **054**). In other embodiments, an overlying stressed material (represented by **054**) is formed first, with the material stack released from the underlying substrate **051** afterwards. Different approaches to the final strained material stack may be useful for different embodiments.

20 Additionally, as discussed above, in some embodiments, the area of the removed portion **055** of the underlying substrate **051** is left as-is (*i.e.* empty as free space) after the portion **055** is removed. In other embodiments, this area is refilled with another material to satisfy any of a variety of desired material, device, circuit, and system characteristics.

FIG. 6 depicts a cross-section of an active material-based structure **060**,
25 similar to that shown in **FIG. 5**, having a strained active material **063** vertically adjacent to an overlying material **064** and an underlying material **062** over an underlying substrate **061**, a portion of which **065** is removed to the bottom of the underlying substrate **061** under an area of the active material **063**, according to another example embodiment of the present invention.

30 As discussed above, to facilitate the application of strain to the active material **063**, a portion of the underlying substrate **061** is removed to expose a region **065**, over which the active material **063** is suspended. The amount of the underlying substrate **061** removed below the active material **063** is based upon desired characteristics of the active material **063** and device/application

considerations. Accordingly, dashed line **066** defines a region of the underlying substrate **061** that is left intact below the underlying material **062**, as representing an exemplary approach to removing less than all of the substrate **061** underlying the suspended portion of the active material **063**.

5 Additionally, as discussed above, in some embodiments, the area of the removed portion **065** of the underlying substrate **061** is left as-is (*i.e.* empty as free space) after the portion **065** is removed. In other embodiments, this area is refilled with another material to satisfy any of a variety of desired material, device, circuit, and system characteristics.

10 **FIG. 7** depicts a cross-section of an active material-based structure **070** having a strained active material **074** horizontally adjacent to other materials **073** and vertically adjacent to an underlying material **072** over an underlying substrate **071**, a portion of which **075** is removed to a depth within the underlying substrate **071** under an area of the active material **074**, according to another example embodiment of the
15 present invention.

As discussed above, to facilitate the application of strain to the active material **074**, a portion of the underlying substrate **071** is removed to expose a region **075**, over which the active material **074** is suspended. The amount of the underlying substrate **071** removed below the active material **074** is based upon
20 desired characteristics of the active material **074** and device/application considerations. Accordingly, dashed line **076** defines a region of the underlying substrate **071** that is left intact below the underlying material **072**, as representing an exemplary approach to removing less than all of the substrate **071** underlying the suspended portion of the active material **074**. Further, the amount of the underlying
25 substrate **071** removed below the active material **074** to a depth within the underlying substrate **071** may also be determined by other desired material and device characteristics, which may include structural integrity of the remaining underlying substrate **071**, device integration schemes, and others.

30 The respective materials **073** and **072** may include one or more of a variety of materials, which can be implemented to strain the active material **074** and/or to hold the active material **074** in a strained state. In some implementations, the horizontally adjacent materials **073** may be used to strain the active material **074**, with the underlying material **072** used to hold the active material **074** in place. In other implementations, the underlying material **072** may be used to strain the active

material **074**, with the horizontally adjacent materials **073** used to hold the active material **074** in place. In still other implementations, both the horizontally adjacent materials **073** and the underlying material **072** may be used to both strain the active material **074** and hold the active material **074** in place. In still other implementations, other processing steps, such as thermal treatments, mechanical bending, and others, may be used to strain the active material **074**, with the horizontally adjacent materials **073** and/or the underlying material **072** used to hold the active material **074** in place.

The specific fabrication process for the structure **070** can be carried out in one or more of a variety of manners, depending upon the desired material and device characteristics. In some embodiments, an initial active material-on-insulator stack (represented by **074**, **072**, and **071**) can be released from the underlying substrate **071** (*e.g.* as shown at region **075**), followed by the formation of horizontally adjacent stressed materials (represented by **073**). In other embodiments, horizontally adjacent stressed materials (represented by **073**) are formed first, with the material stack released from the underlying substrate **071** afterwards. Different approaches to the final strained material stack may be useful for different embodiments.

Additionally, as discussed above, in some embodiments, the area of the removed portion **075** of the underlying substrate **071** is left as-is (*i.e.* empty as free space) after the portion **075** is removed. In other embodiments, this area is refilled with another material to satisfy any of a variety of desired material, device, circuit, and system characteristics.

FIG. 8 depicts a cross-section of an active material-based structure **080**, similar to that shown in **FIG. 7**, having a strained active material **084** horizontally adjacent to other materials **083** and vertically adjacent to an underlying material **082** over an underlying substrate **081**, a portion of which **085** is removed to the bottom of the underlying substrate **081** under an area of the active material **084**, according to another example embodiment of the present invention.

As discussed above, to facilitate the application of strain to the active material **084**, a portion of the underlying substrate **081** is removed to expose a region **085**, over which the active material **084** is suspended. The amount of the underlying substrate **081** removed below the active material **084** is based upon desired characteristics of the active material **084** and device/application considerations. Accordingly, dashed line **086** defines a region of the underlying

substrate **081** that is left intact below the underlying material **082**, as representing an exemplary approach to removing less than all of the substrate **081** underlying the suspended portion of the active material **084**.

Additionally, as discussed above, in some embodiments, the area of the removed portion **085** of the underlying substrate **081** is left as-is (*i.e.* empty as free space) after the portion **085** is removed. In other embodiments, this area is refilled with another material to satisfy any of a variety of desired material, device, circuit, and system characteristics.

FIG. 9 depicts a cross-section of an active material-based structure **090** having a strained active material **093** vertically adjacent to an overlying material **094** and an underlying material **092** over an underlying substrate **091**, where a portion **095** of the underlying material **092** is removed under an area of the active material **093**, according to another example embodiment of the present invention.

To facilitate the application of strain to the active material **093**, a portion of the underlying material **092** is removed to expose a region **095**, over which the active material **093** is suspended. The amount of the underlying material **092** removed below the active material **093** is based upon desired characteristics of the active material **093** and device/application considerations. Accordingly, dashed line **096** defines a region of the underlying material **092** that is left intact below the active material **093**, as representing an exemplary approach to removing less than all of the material **092** underlying the suspended portion of the active material **093**.

Additionally, in some embodiments, the area of the removed portion **095** of the underlying material **092** is left as-is (*i.e.* empty as free space) after the portion **095** is removed. In other embodiments, this area is refilled with another material to satisfy any of a variety of desired material, device, circuit, and system characteristics.

FIG. 10 depicts a cross-section of an active material-based structure **100** having a strained active material **103** vertically adjacent to an overlying material **104** and an underlying material **102** over an underlying substrate **101**, where a portion **105** of the underlying material **102** and underlying substrate **101** is removed to a depth within the underlying substrate **101** under an area of the active material **103**, according to another example embodiment of the present invention.

To facilitate the application of strain to the active material **103**, a portion of the underlying material **102** and underlying substrate **101** is removed to expose a

region **105**, over which the active material **103** is suspended. The amount of the underlying material **102** and underlying substrate **101** removed below the active material **103** is based upon desired characteristics of the active material **103** and device/application considerations. Accordingly, dashed line **106** defines a region of the underlying material **102** that is left intact below the active material **103**, as representing an exemplary approach to removing less than all of the material **102** underlying the suspended portion of the active material **103**. Further, the amount of the underlying substrate **101** removed below the material **102** to a depth within the underlying substrate **101** may also be determined by other desired material and device characteristics, which may include structural integrity of the remaining underlying substrate **101**, device integration schemes, and others.

Additionally, in some embodiments, the area of the removed portion **105** of the underlying material **102** and underlying substrate **101** is left as-is (*i.e.* empty as free space) after the portion **105** is removed. In other embodiments, this area is refilled with another material to satisfy any of a variety of desired material, device, circuit, and system characteristics.

FIG. 11 depicts a cross-section of an active material-based structure **110**, similar to that shown in **FIG. 10**, having a strained active material **113** vertically adjacent to an overlying material **114** and an underlying material **112** over an underlying substrate **111**, where a portion **115** of the underlying material **112** and underlying substrate **111** is removed to the bottom of the underlying substrate **111** under an area of the active material **113**, according to another example embodiment of the present invention.

As discussed above, to facilitate the application of strain to the active material **113**, a portion of the underlying material **112** and underlying substrate **111** is removed to expose a region **115**, over which the active material **113** is suspended. The amount of the underlying material **112** and underlying substrate **111** removed below the active material **113** is based upon desired characteristics of the active material **113** and device/application considerations. Accordingly, dashed line **116** defines a region of the underlying material **112** that is left intact below the active material **113**, as representing an exemplary approach to removing less than all of the material **112** underlying the suspended portion of the active material **113**.

Additionally, as discussed above, in some embodiments, the area of the removed portion **115** of the underlying material **112** and underlying substrate **111** is

left as-is (*i.e.* empty as free space) after the portion **115** is removed. In other embodiments, this area is refilled with another material to satisfy any of a variety of desired material, device, circuit, and system characteristics.

FIG. 12 depicts a cross-section of an active material-based structure **120** having a strained active material **124** horizontally adjacent to other materials **123** and vertically adjacent to an underlying material **122** over an underlying substrate **121**, where a portion **125** of the underlying material **122** is removed under an area of the active material **124**, according to another example embodiment of the present invention.

As discussed above, to facilitate the application of strain to the active material **124**, a portion of the underlying material **122** is removed to expose a region **125**, over which the active material **124** is suspended. The amount of the underlying material **122** removed below the active material **124** is based upon desired characteristics of the active material **124** and device/application considerations.

Accordingly, dashed line **126** defines a region of the underlying material **122** that is left intact below the active material **124**, as representing an exemplary approach to removing less than all of the material **122** underlying the suspended portion of the active material **124**.

Additionally, in some embodiments, the area of the removed portion **125** of the underlying material **122** is left as-is (*i.e.* empty as free space) after the portion **125** is removed. In other embodiments, this area is refilled with another material to satisfy any of a variety of desired material, device, circuit, and system characteristics.

FIG. 13 depicts a cross-section of an active material-based structure **130** having a strained active material **134** horizontally adjacent to other materials **133** and vertically adjacent to an underlying material **132** over an underlying substrate **131**, where a portion of the underlying material **132** and underlying substrate **131** is removed to a depth within the underlying substrate **131** under an area of the active material **134**, according to another example embodiment of the present invention.

As discussed above, to facilitate the application of strain to the active material **134**, a portion of the underlying material **132** and underlying substrate **131** is removed to expose a region **135**, over which the active material **134** is suspended. The amount of the underlying material **132** and underlying substrate **131** removed below the active material **134** is based upon desired characteristics of the active

material **134** and device/application considerations. Accordingly, dashed line **136** defines a region of the underlying material **132** that is left intact below the active material **134**, as representing an exemplary approach to removing less than all of the material **132** underlying the suspended portion of the active material **134**. Further,
5 the amount of the underlying substrate **131** removed below the material **132** to a depth within the underlying substrate **131** may also be determined by other desired material and device characteristics, which may include structural integrity of the remaining underlying substrate **131**, device integration schemes, and others.

Additionally, in some embodiments, the area of the removed portion **135** of
10 the underlying material **132** and underlying substrate **131** is left as-is (*i.e.* empty as free space) after the portion **135** is removed. In other embodiments, this area is refilled with another material to satisfy any of a variety of desired material, device, circuit, and system characteristics.

FIG. 14 depicts a cross-section of an active material-based structure **140**,
15 similar to that shown in **FIG. 13**, having a strained active material **144** horizontally adjacent to other materials **143** and vertically adjacent to an underlying material **142** over an underlying substrate **141**, where a portion **145** of the underlying material **142** and underlying substrate **141** is removed to the bottom of the underlying substrate **141** under an area of the active material **144**, according to another example
20 embodiment of the present invention.

As discussed above, to facilitate the application of strain to the active material **144**, a portion of the underlying material **142** and underlying substrate **141** is removed to expose a region **145**, over which the active material **144** is suspended. The amount of the underlying material **142** and underlying substrate **141** removed
25 below the active material **144** is based upon desired characteristics of the active material **144** and device/application considerations. Accordingly, dashed line **146** defines a region of the underlying material **142** that is left intact below the active material **144**, as representing an exemplary approach to removing less than all of the material **142** underlying the suspended portion of the active material **144**.

30 Additionally, as discussed above, in some embodiments, the area of the removed portion **145** of the underlying material **142** and underlying substrate **141** is left as-is (*i.e.* empty as free space) after the portion **145** is removed. In other embodiments, this area is refilled with another material to satisfy any of a variety of desired material, device, circuit, and system characteristics.

The strained-material structures as described herein may be formed in one or more of a variety of shapes and arrangements, including but not limited to those shown in **FIGS. 1-14** and in the Appendix, which forms part of this patent document.

The following describes various embodiments, which may be applicable to one or more of the figures as described above, as well as to other embodiments described herein.

In one embodiment, a three-layer active material structure includes a 30nm-thick diamond-like carbon (DLC) layer on a 100nm-thick active material film, which is on a 100nm-thick DLC layer. The material stack is partially suspended over a 5 μ m hole in a silicon substrate, which facilitates the application of tensile strain to the active material film, by one or both DLC layers. In some implementations, greater than about 0.3% biaxial tensile strain is induced in the active material layer, which corresponds to a direct bandgap reduction in excess of 30meV and a greater than 60nm shift in the absorption edge towards longer wavelengths for the specific exemplary case of a germanium active layer.

In another embodiment, a four-layer active material structure includes a 30nm-thick DLC layer on a 100nm-thick active material layer, which is on a 100nm-thick silicon nitride layer (Si_3N_4) on a 30nm-thick silicon dioxide (SiO_2) layer, and the material stack is partially suspended over a 5 μ m hole in a silicon substrate. In some implementations for the case of a germanium active layer, a tensile strain that is greater than about 0.4% is induced in the active material layer, which corresponds to a 40meV reduction in the direct bandgap and at least an 80nm absorption edge shift towards longer wavelengths. In one implementation, the DLC-active material- Si_3N_4 - SiO_2 material stack is supported by beams at four locations from an underlying silicon substrate. In other implementations, such as those involving the use of horizontally-located stressor materials (e.g. as **073** of **FIG. 7**), well over 2% strain is induced upon an active material layer. In fact, for such a configuration as well as others, arbitrary amounts of strain can be applied depending on structure geometries, material compositions, and other characteristics. For these and other implementations, the amount of strain applied to a material can be set up to a threshold including and below which the material is capable of remaining intact under the strain, where such a threshold depends upon characteristics and arrangement of the material and its interactions with surrounding materials.

The materials as described herein may be formed and stressed using one or more of a variety of approaches. In some embodiments, an active material in a suspended material stack is relaxed, prior to stressing with another adjacent material as discussed above. In other embodiments, the active material is pre-stressed, prior to further stressing with another adjacent material. These approaches may be used with a variety of configurations, including an active material-on-insulator configuration, with a stressing material formed over the starting material stack after pre-relaxation or pre-stressing.

The substrate material over which the active material stack is formed can also be formed and/or arranged using one or more of a variety of approaches. In some embodiments, an underlying substrate is chosen to induce different properties in the active material. For example, an underlying substrate or material may be selected and used to set the crystal orientation and/or the initial strain state of the active material, where the active material is first formed on the substrate and subsequently suspended via removal of a portion of the substrate.

In addition, the shape and amount of substrate material that is etched or otherwise removed to suspend the active material stack can also be used to set the strain experienced by the active material. For instance, substrate material may be left in certain regions to add structural integrity to the active material stack while reducing the strain therein.

In addition, subsequent to the etching or otherwise removal of materials underlying an active material to allow for strain transfer, other materials may be formed to reconnect the active material to the underlying materials and/or substrate in whole or in part. For instance, a material may be used to refill the space underneath a strained active material stack in order to provide enhanced structural integrity, improved thermal conductivity, or any of other desired characteristics once strain has been introduced in the active material.

Different types of materials can be used to set the strain of active materials as described herein. For example, one embodiment is directed to using a transparent film on one or opposing sides of an active material film (e.g. as **064** and/or **062** of **FIG. 6**) to permit optical detection or emission from the active material film. In another embodiment, a highly stressed metal is deposited on an active material film as a capping layer (e.g. as **064** of **FIG. 6**) with a transparent dielectric (e.g. as **062** of **FIG. 6**) underneath the active material film. In this embodiment, the

top metal could both induce strain in the active material and serve as electrode(s), while the optical absorption/emission is accomplished from the backside. In other embodiments, the size and geometry of a capping layer (e.g. as **013** of **FIG. 1**) is set to induce highly localized strains (e.g. with varying thickness, composition and/or location of a top layer), or to induce small, uniform strains (e.g. with a layer **013** across an entire active material film, or extending beyond such a film).

Suspended material stacks including an active material as discussed herein may be formed in one or more of a variety of shapes. In some implementations, the shape of the suspended material stack is set to correspondingly set characteristics of the active material, such as those relating to strain, stress gradient, light absorption, light emission, charge carrier mobility, and charge carrier scattering statistics, among others.

EXAMPLE 1

DEVICES BUILT ON STRAINED ACTIVE LAYERS

An active-on-other material stack (e.g. germanium-on-insulator) is prepared by any of several methods. The starting material stack may be part of a semiconductor (e.g. silicon) wafer that includes fabrication of CMOS or other circuitry thereon. The active layer is patterned using photolithographic techniques common in semiconductor fabrication. In one example, this could include the coating, exposure, and development of a photoresist material that serves as a protective mask during subsequent etch and removal of the exposed active layer areas. The starting active layer may have a thickness determined by the need to satisfy any of various material, mechanical, and device specifications for a given application. For example, the range of active layer thicknesses appropriate for one such application may be 100Å-10000Å.

Another material under internal tensile stress is then deposited non-selectively on the patterned active layer and surrounding wafer surface. In one example, this deposited material may be a silicon nitride film deposited using any of several available techniques, including low-pressure chemical vapor deposition (LPCVD), plasma-enhanced chemical vapor deposition (PECVD), sputtering, etc. The thickness of the deposited stressed film is also determined by material, mechanical, and device specifications depending on the application. For example, for a 2500Å-thick active layer, a stressor layer with thickness in the range of 2500Å-

10000Å may be appropriate, depending on the application and other factors. The salient feature of the deposited film is the presence of internal tensile stress due to thermal considerations, internal atomic structure, or other factors. The deposited stressor layer is then patterned and etched to form structures physically connected to and overlapping the patterned active layer in some areas. In one example, a patterned active region may be rectangular, with the stressor layer etched to form two separate stressor regions on the wafer surface near opposite ends of the active region and partially overlapping the opposite active area ends in direct physical contact (e.g. similar to **070** in **FIG. 7**).

A photolithography process is then done to expose regions of the wafer surface near the active layer and stressor structures while protecting the rest of the wafer surface. Any of several etch procedures can then be done to free the active layer and part of the stressor structures from the underlying materials. In one example, a selective etch can be done to isotropically remove the material that was immediately underneath the active layer in the starting film stack (e.g. the oxide underlayer in a GOI wafer) while leaving all other materials intact (e.g. as **125** of **FIG. 12**). In another example, an etch through the underlying material layer (e.g. the oxide underlayer in a GOI wafer) can be done to expose the wafer substrate or second underlying material, which is then isotropically etched underneath the active layer and part of the stressor structures (e.g. as **075** of **FIG. 7**).

The stressor structures that are connected to the patterned active regions and have been freed from the underlying materials then relax and release their internal tensile stress through contraction. Provided the active layer is relatively more compliant, the internal stress in the released stressor regions is then transferred to the suspended patterned active regions. The void left underneath an active region and part of the stressor structures as a result of the release etch can be left as-is or refilled using another material if desired, depending on application specifics. Electronic and/or optoelectronic devices can then be built on the strained active layer using a combination of fabrication steps, including but not limited to ion implantation steps, metal electrode deposition and patterning, and other processes used to fabricate various devices.

EXAMPLE 2

PHOTODETECTORS

Following the general method of Example 1, a photodetector can be made on an active layer that is strained either prior to device fabrication or as the final step in the device fabrication process.

For example, a strained metal-semiconductor-metal (MSM) photodetector can be fabricated by adding a metal evaporation and photoresist lift-off lithography process after the method of Example 1 is followed to apply strain to an active layer meant to serve as the absorption medium in the device. In one specific process example, a spray-coating system can be used to deposit photoresist on all accessible material surfaces after the release etch is done for the strain transfer. Then, after photoresist exposure and developing to form electrode patterns, a metal electrode stack (*e.g.* 150Å of Titanium followed by 350Å of Gold) can be evaporated non-selectively on the wafer surface. A metal lift-off process consisting of soaking the wafer in a solvent (*e.g.* acetone) to dissolve the remaining photoresist and remove the metal films lying on top of the dissolving photoresist can be done to leave the desirable electrode pattern in electrical contact with the strained active material. In an alternate process example, the above metallization steps can be inserted into the fabrication process of Example 1 before the release etch is performed. In this case, the MSM photodetector is first formed on the active material prior to the introduction of strain via the removal of underlying materials and/or substrate in the regions of interest.

As another photodetector device example, a strained *pin* photodetector can be fabricated by combining the metallization steps described above for the MSM photodetector device and engineering of the active material itself. For example, the *pin* device fabrication process may commence with the active material comprised of several layers of doped semiconductor arranged either vertically or horizontally to obtain a region of intrinsic semiconductor sandwiched between regions of *n*-type and *p*-type semiconductors (*e.g.* via the epitaxial growth of three layers of semiconductor under different in-situ doping conditions). The metallization and electrode definition steps would then be designed to yield electrical contact to the *n*- and *p*- type regions. As an alternate process, the *pin* doping arrangement of the active layer could be achieved by starting with an intrinsic semiconductor that is subsequently doped via patterned ion implantation steps at any of various points in the rest of the device

fabrication process.

EXAMPLE 3

LIGHT-EMITTING DIODES

5 Following the general method of Example 1, a light-emitting diode (LED) can be made on an active layer that is strained either prior to device fabrication or as the final step in the device fabrication process. For example, a strained *pin* LED can be fabricated by combining the methods of Example 1 and Example 2 for the case of a *pin* photodetector.

10 As an alternate device example, a *pn* LED can be fabricated by combining the methods of Example 1 and Example 2 for the case of a *pin* photodetector but removing the intrinsic semiconductor from the material stack. In the case of epitaxially-obtained films, the starting active layer in this case could be comprised of two epitaxially-grown semiconductors, one of *n*-type doping and the other of *p*-type
15 doping. Alternately, the starting active layer could be a single semiconductor of either *n*- or *p*-type doping. A subsequent ion implantation or other doping process can be done to introduce the opposite doping species to desired regions of the active layer to selectively change the electrical character of those regions. For example, in the case of an *n*-type starting film, *p*-type dopants could be ion implanted into certain
20 regions of the active layer. In this case, enough of the implanted species would need to be introduced to counter the dopants already present and invert the character of the active layer in those regions.

EXAMPLE 4

PHOTONIC CRYSTALS

25 Following the general method of Example 1, a photonic crystal can be made on an active layer that is strained either prior to device fabrication or as the final step in the device fabrication process.

30 For example, a strained photonic crystal can be fabricated by incorporating in the active layer pattern of Example 1 an additional pattern of holes of a desired size and arrangement to yield a photonic crystal in the active layer. In this approach, the hole pattern comprising the photonic crystal and the containing active layer pattern in which the holes are to be incorporated would be defined and etched simultaneously. Subsequent processing could proceed as normally described in the

method of Example 1, with release etching done as normal or modified to also act through the photonic crystal holes in the active layer. The latter approach may be chosen to enhance the release etch rate, uniformity, mechanical integrity, and other factors of the active layer and device.

5 In an alternate process example, the photonic crystal hole pattern may be incorporated in the active layer after the release etch is performed. In this case, a spray-coating system may be used to deposit photoresist on the strained active layer. Exposure and develop steps following by etching would then be done to transfer the desired hole pattern onto the active layer, yielding a strained photonic
10 crystal.

Without limitation, a variety of embodiments are directed to implementations consistent with those presented in the attached Appendix, which forms part of this patent document. For instance, one or more embodiments as
15 described herein and/or as part of the claims may be implemented with one or more embodiments shown in and/or described in connection with the Appendix, alone, in combination with other embodiments, or in connection with other embodiments not described here.

The various embodiments described above are provided by way of
20 illustration and should not be construed to limit the invention. Based upon the above discussion and illustrations, those skilled in the art will recognize that various modifications and changes may be made to the present invention without strictly following the exemplary embodiments and applications illustrated and described herein. Such modifications and changes do not depart from the true spirit and scope
25 of the present invention, including that set forth in the following claims.

APPENDIX

Example embodiments are herein presented in the non-limiting example context of Ge-based active materials, Si_3N_4 -based stressor materials, SiO_2 -based
5 intermediate dielectric materials, and Si-based substrates.

MSM Photodetectors

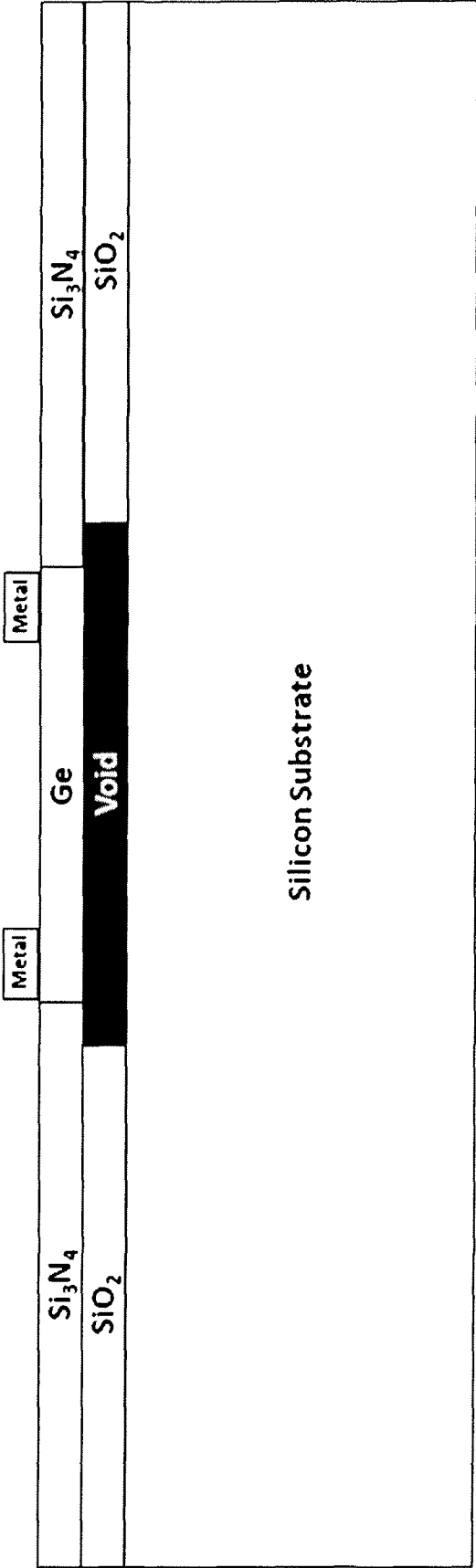


FIG. A-1

PIN Photodetectors, LEDs

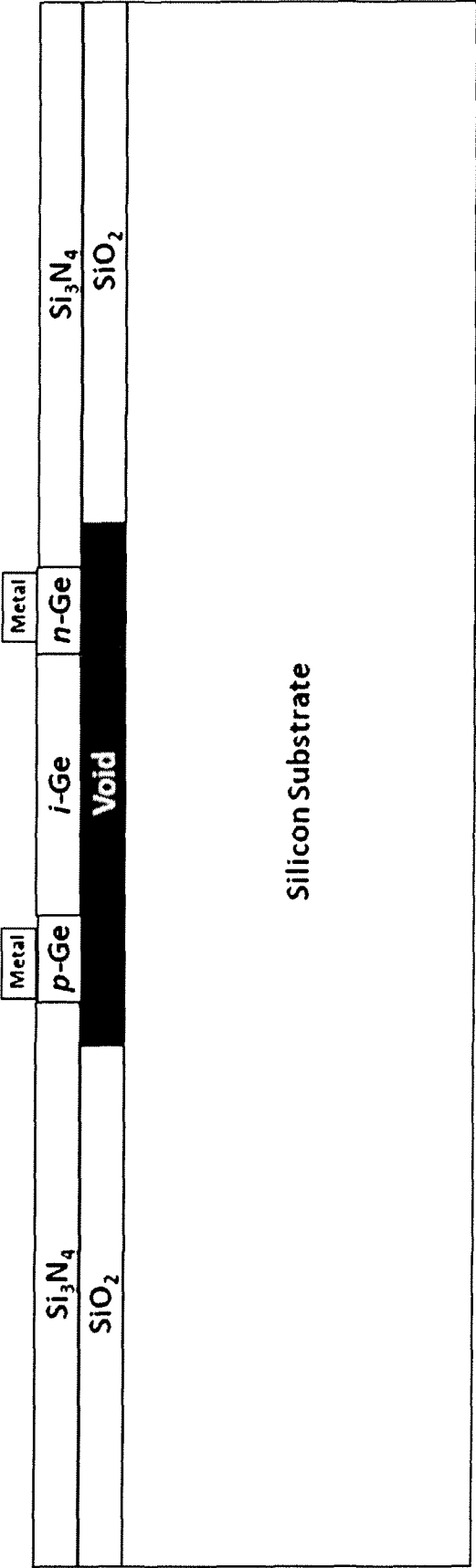


FIG. A-2

PIN Photodetectors, LEDs

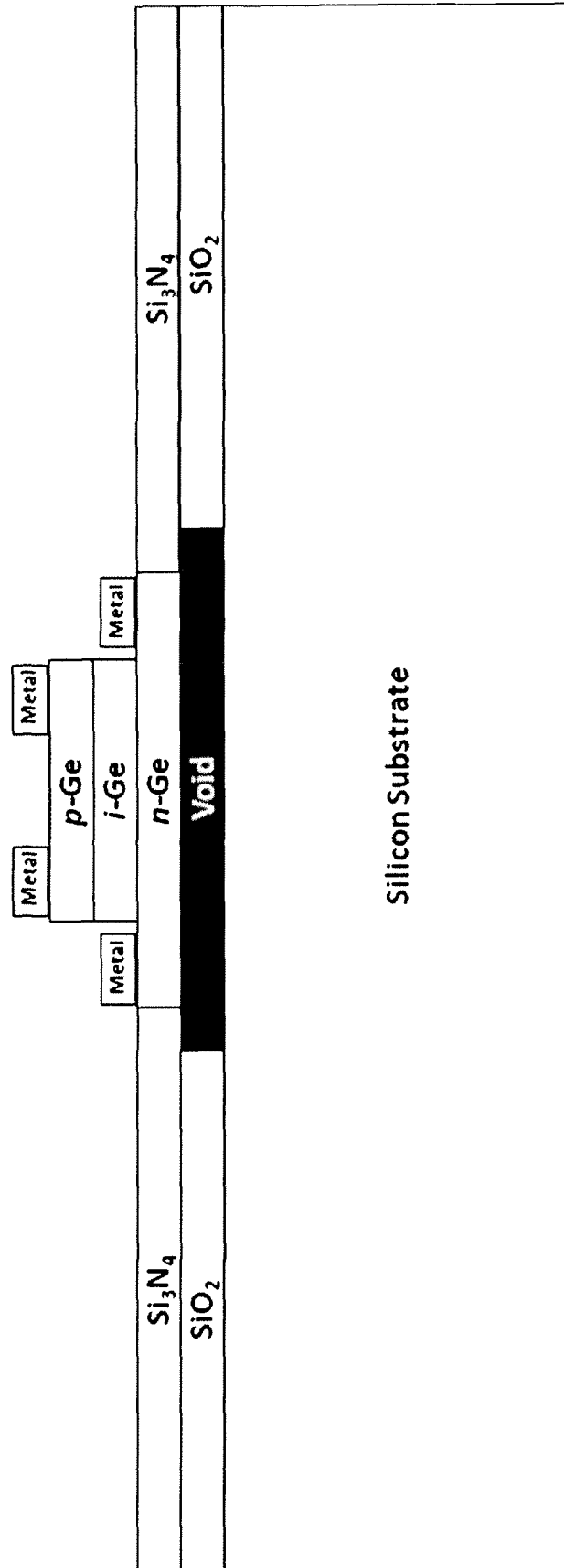


FIG. A-3

Edge-Emitting Laser Diodes

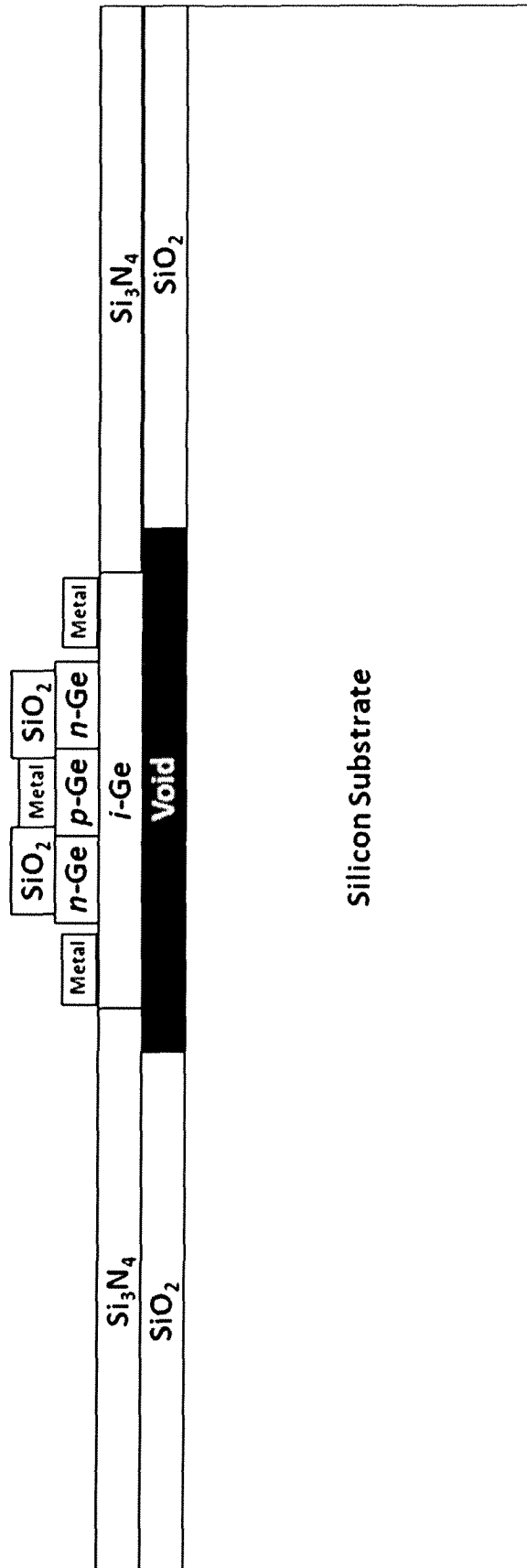


FIG. A-4

Waveguide Lasers/Modulators

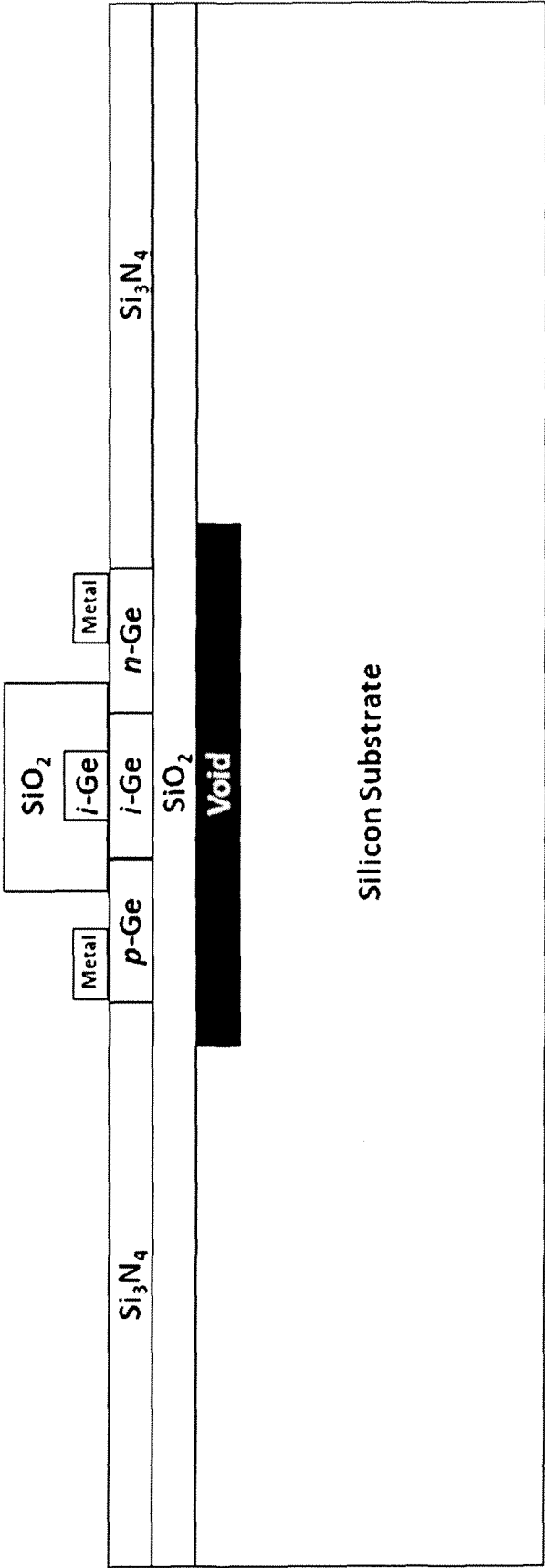


FIG. A-5

Quantum Well Modulators

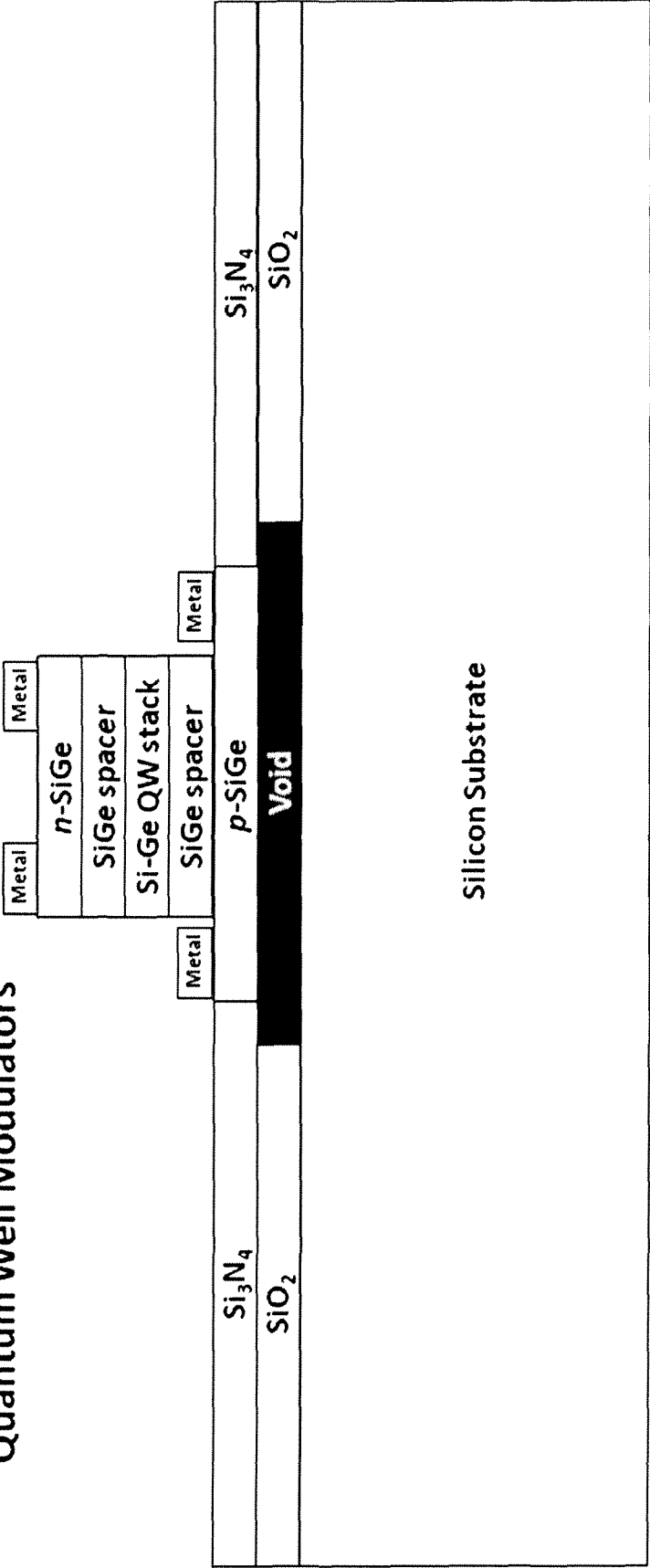


FIG. A-6

Photonic Crystals

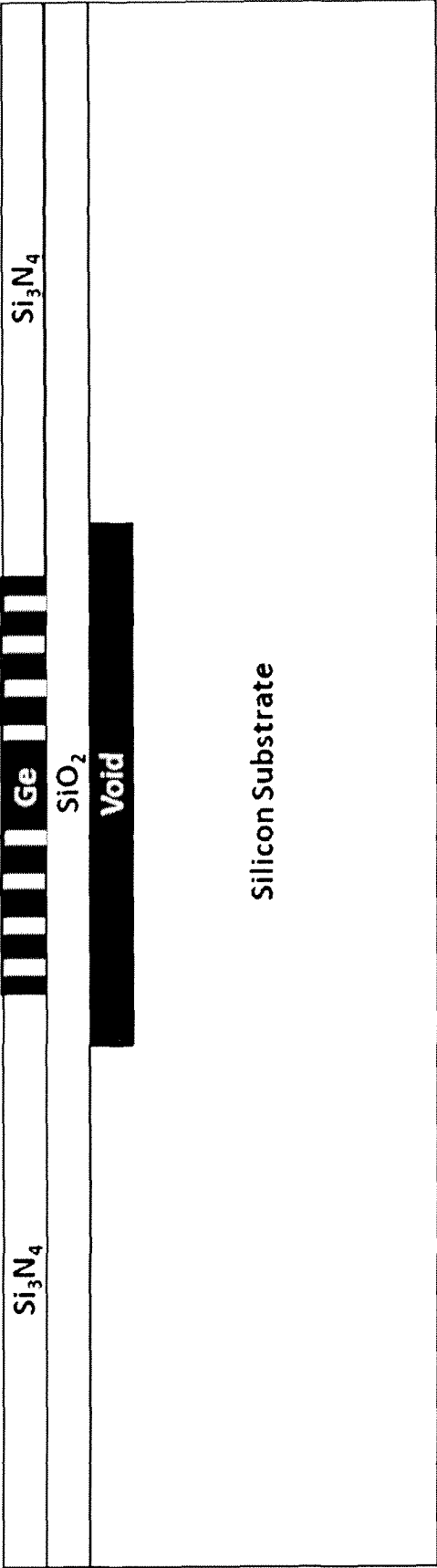


FIG. A-7

MOSFETs

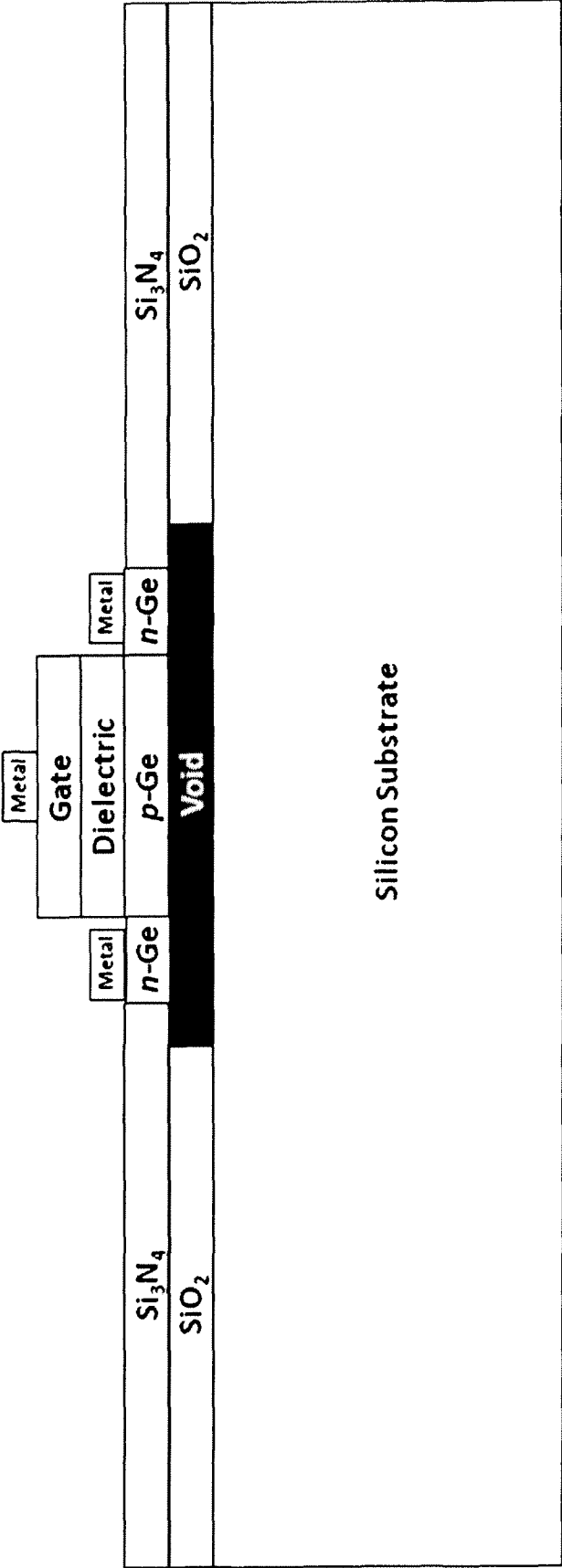


FIG. A-8

Claims listing:

1. A semiconductor device comprising:
 - a substrate;
 - a material stack including
 - an active material over the substrate,
 - a first material connected to a surface of the active material,
 - the first material being configured and arranged to induce a strain in the active material, and
 - at least one of the first material and substrate being configured and arranged to mitigate relaxation of the strain induced in the active material;
 - and
 - a support structure to suspend a portion of the material stack over a portion of the substrate.
2. The device of claim 1, wherein the device is selected from at least one of an electronic device and an optoelectronic device.
3. The device of claim 1, wherein the active material includes a semiconductor material.
4. The device of claim 1, wherein the active material can include at least one of several materials formed on top of each other and several materials arranged horizontally in physical contact.
5. The device of claim 1, wherein the first material includes a material vertically adjacent to, and interfacing with a surface of, the active material.
6. The device of claim 1, wherein the first material includes a material horizontally adjacent to, and interfacing with a surface of, the active material.
7. The device of claim 1, wherein the first material is configured and arranged to induce a strain in the active material in order to set at least one of an electronic characteristic and optoelectronic characteristic of the

active material.

8. The device of claim **1**, wherein the first material is localized to a portion of the active material in order to induce a localized strain at said portion.

5

9. The device of claim **1**, wherein the support structure is part of the substrate and is configured to suspend a portion of the material stack over a removed portion of the substrate that extends horizontally between portions of the support structure.

10

10. The device of claim **9**, wherein the removed portion of the substrate extends vertically to a depth within the substrate but not to the bottom of the substrate.

15

11. The device of claim **9**, wherein the removed portion of the substrate extends vertically to the bottom of the substrate.

12. The device of claim **9**, wherein an area of the removed portion of the substrate is refilled with another material.

20

13. A semiconductor device comprising:

a substrate;

a material stack including

a first material over the substrate,

25

an active material on the first material,

a second material connected to a surface of the active material,

at least one of the first and second materials being configured and arranged to induce a strain in the active material, and

30

at least one of the first and second materials being configured and arranged to mitigate relaxation of the strain induced in the active material; and

a support structure to suspend a portion of the material stack over a portion of the substrate.

14. The device of claim **13**, wherein the device is selected from at least one of an electronic device and an optoelectronic device.
- 5 15. The device of claim **13**, wherein the active material includes a semiconductor material.
- 10 16. The device of claim **13**, wherein the active material can include at least one of several materials formed on top of each other and several materials arranged horizontally in physical contact.
17. The device of claim **13**, wherein the first material is an insulator material, and the active material and insulator material form an active material-on-insulator stack.
- 15 18. The device of claim **13**, wherein the second material includes a material vertically adjacent to, and interfacing with a surface of, the active material.
19. The device of claim **13**, wherein the second material includes a material horizontally adjacent to, and interfacing with a surface of, the active material.
- 20 20. The device of claim **13**, wherein at least one of the first and second materials is configured and arranged to induce a strain in the active material in order to set at least one of an electronic characteristic and optoelectronic characteristic of the active material.
- 25 21. The device of claim **13**, wherein the first material is the strain-inducing material and is localized to a portion of the active material in order to induce a localized strain at said portion.
- 30 22. The device of claim **13**, wherein the second material is the strain-inducing material and is localized to a portion of the active material in order to induce a localized strain at said portion.

23. The device of claim **13**, wherein the support structure is part of the substrate and is configured to suspend a portion of the material stack over a removed portion of the substrate that extends horizontally between portions of the support structure.

5

24. The device of claim **23**, wherein the removed portion of the substrate extends vertically to a depth within the substrate but not to the bottom of the substrate.

10

25. The device of claim **23**, wherein the removed portion of the substrate extends vertically to the bottom of the substrate.

26. The device of claim **23**, wherein an area of the removed portion of the substrate is refilled with another material.

15

27. A semiconductor device comprising:

a substrate;

a first material over the substrate;

a material stack including

20

an active material on the first material,

a second material connected to a surface of the active material,

at least one of the first and second materials being configured and

arranged to induce a strain in the active material, and

at least one of the first and second materials being configured and

25

arranged to mitigate relaxation of the strain induced in the active material;

and

a support structure to suspend a portion of the material stack over a portion of the first material.

30

28. The device of claim **27**, wherein the device is selected from at least one of an electronic device and an optoelectronic device.

29. The device of claim **27**, wherein the active material includes a semiconductor material.

- 5
30. The device of claim **27**, wherein the active material can include at least one of several materials formed on top of each other and several materials arranged horizontally in physical contact.
31. The device of claim **27**, wherein the first material is an insulator material, and the active material and insulator material form an active material-on-insulator stack.
- 10 32. The device of claim **27**, wherein the second material includes a material vertically adjacent to, and interfacing with a surface of, the active material.
33. The device of claim **27**, wherein the second material includes a material horizontally adjacent to, and interfacing with a surface of, the active material.
- 15
34. The device of claim **27**, wherein at least one of the first and second materials is configured and arranged to induce a strain in the active material in order to set at least one of an electronic characteristic and optoelectronic characteristic of the active material.
- 20
35. The device of claim **27**, wherein the first material is the strain-inducing material and is localized to a portion of the active material in order to induce a localized strain at said portion.
- 25
36. The device of claim **27**, wherein the second material is the strain-inducing material and is localized to a portion of the active material in order to induce a localized strain at said portion.
- 30 37. The device of claim **27**, wherein the support structure is part of the first material and is configured to suspend the material stack over a removed portion of the first material that extends horizontally between portions of the support structure.

38. The device of claim **37**, wherein the removed portion of the first material extends vertically to a depth within the first material but not to the bottom of the first material.

39. The device of claim **37**, wherein the removed portion of the first material extends vertically to the bottom of the first material.

40. The device of claim **37**, wherein an area of the removed portion of the first material is refilled with another material.

41. A semiconductor device comprising:

a substrate;

a first material over the substrate;

a material stack including

an active material on the first material,

a second material connected to a surface of the active material,

at least one of the first and second materials being configured and arranged to induce a strain in the active material, and

at least one of the first and second materials being configured and arranged to mitigate relaxation of the strain induced in the active material; and

a support structure to suspend a portion of the material stack over a portion of the first material and substrate.

42. The device of claim **41**, wherein the device is selected from at least one of an electronic device and an optoelectronic device.

43. The device of claim **41**, wherein the active material includes a semiconductor material.

44. The device of claim **41**, wherein the active material can include at least one of several materials formed on top of each other and several materials arranged horizontally in physical contact.

45. The device of claim **41**, wherein the first material is an insulator material, and the active material and insulator material form an active material-on-insulator stack.
- 5 46. The device of claim **41**, wherein the second material includes a material vertically adjacent to, and interfacing with a surface of, the active material.
- 10 47. The device of claim **41**, wherein the second material includes a material horizontally adjacent to, and interfacing with a surface of, the active material.
- 15 48. The device of claim **41**, wherein at least one of the first and second materials is configured and arranged to induce a strain in the active material in order to set at least one of an electronic characteristic and optoelectronic characteristic of the active material.
- 20 49. The device of claim **41**, wherein the first material is the strain-inducing material and is localized to a portion of the active material in order to induce a localized strain at said portion.
- 25 50. The device of claim **41**, wherein the second material is the strain-inducing material and is localized to a portion of the active material in order to induce a localized strain at said portion.
- 30 51. The device of claim **41**, wherein the support structure is part of the first material and substrate and is configured to suspend the material stack over a removed portion of the first material and substrate that extends horizontally between portions of the support structure.
52. The device of claim **51**, wherein the removed portion of the first material and substrate extends vertically to a depth within the substrate but not to the bottom of the substrate.
53. The device of claim **51**, wherein the removed portion of the first material

and substrate extends vertically to the bottom of the substrate.

54. The device of claim **51**, wherein an area of the removed portion of the first material and substrate is refilled with another material.

5

55. An intermediate-manufacture semiconductor device comprising:
a substrate;
an active material;
a strain-inducing material connected to a surface of the active material
and configured and arranged to induce a strain in the active material; and
a support structure to suspend a portion of the active material over a
portion of the substrate.

10

56. The device of claim **55**, wherein the device is selected from at least one of an electronic device and an optoelectronic device.

15

57. The device of claim **55**, wherein the active material includes a semiconductor material.

58. The device of claim **55**, wherein the active material can include at least one of several materials formed on top of each other and several materials arranged horizontally in physical contact.

20

59. The device of claim **55**, wherein the strain-inducing material includes a material vertically adjacent to, and interfacing with a surface of, the active material.

25

60. The device of claim **55**, wherein the strain-inducing material includes a material horizontally adjacent to, and interfacing with a surface of, the active material.

30

61. The device of claim **55**, wherein the strain-inducing material is configured and arranged to induce a strain in the active material in order to set at least one of an electronic characteristic and optoelectronic characteristic of

the active material.

5 62. The device of claim **55**, wherein the strain-inducing material is localized to a portion of the active material in order to induce a localized strain at said portion.

63. The device of claim **55**, wherein the support structure is part of the substrate.

10 64. The device of claim **55**, wherein an area of the region over which the active material is suspended is filled with another material.

15 65. An intermediate-manufacture semiconductor device comprising:
 a substrate;
 a strained active material;
 a material connected to a surface of the strained active material and configured and arranged to mitigate relaxation of the strain induced in the strained active material; and
 a support structure to suspend a portion of the strained active material
20 over a portion of the substrate.

66. The device of claim **65**, wherein the device is selected from at least one of an electronic device and an optoelectronic device.

25 67. The device of claim **65**, wherein the strained active material includes a semiconductor material.

30 68. The device of claim **65**, wherein the strained active material can include at least one of several materials formed on top of each other and several materials arranged horizontally in physical contact.

69. The device of claim **65**, wherein the material includes a material vertically adjacent to, and interfacing with a surface of, the active material.

70. The device of claim **65**, wherein the material includes a material horizontally adjacent to, and interfacing with a surface of, the active material.
- 5 71. The device of claim **65**, further including a strain-inducing material contacting a portion of the strained active material, prior to the active material being strained, to induce a strain therewith.
- 10 72. The device of claim **65**, wherein the support structure is part of the substrate.
73. The device of claim **65**, wherein an area of the region over which the strained active material is suspended is filled with another material.
- 15 74. A method of manufacturing a semiconductor device, the method comprising:
forming a material stack by
forming an active material on a substrate, and
forming a first material connected to a surface of the active material;
20 removing a portion of the substrate below an area of the material stack to suspend a portion of the material stack over a portion of the substrate, using a portion of the substrate to support the suspended material stack; and
using the first material to induce a strain in the active material.
- 25 75. The method of claim **74**, wherein at least part of the material stack is formed prior to the removal of a portion of the substrate and suspension of a portion of the material stack over a portion of the substrate.
- 30 76. The method of claim **74**, wherein at least part of the material stack is formed after the removal of a portion of the substrate.
77. The method of claim **74**, wherein the first material is configured and arranged to induce a strain in the active material.

78. The method of claim **74**, wherein at least one of the steps of forming a first material includes

selecting at least one of an electronic characteristic and optoelectronic characteristic for the active material,

selecting a configuration and arrangement of the first material to induce a strain in the active material in order to set at least one of an electronic characteristic and optoelectronic characteristic of the active material to the selected electronic characteristic or optoelectronic characteristic, and

forming the first material having the selected configuration and arrangement.

79. The method of claim **74**, wherein removing a portion of the substrate below an area of the material stack includes using an etch process starting at the topside of the substrate.

80. The method of claim **74**, wherein removing a portion of the substrate below an area of the material stack includes using an etch process starting at the backside of the substrate.

81. The method of claim **74**, wherein using the first material to induce a strain in the active material includes

forming the first material connected to a surface of the active material after removing a portion of the substrate to suspend a portion of the active material, and

using the first material to induce a strain in the suspended portion of the active material.

82. The method of claim **74**, wherein using the first material to induce a strain in the active material includes

removing a portion of the substrate to suspend a portion of the material stack, after forming the first material connected to a surface of the active material, and

using the first material to induce a strain in the suspended portion of

the active material.

5 83. The method of claim **74**, further including removing the material stack from the substrate, after a strain has been induced therein, and installing the material stack in at least one of an electronic device and optoelectronic device.

10 84. The method of claim **74**, further including refilling an area of the removed portion of the substrate with *another material*.

85. A method of manufacturing a semiconductor device, the method comprising:

forming a material stack by

forming a first material on a substrate,

15 forming an active material on the first material, and

forming a second material connected to a surface of the active material,

20 removing a portion of the substrate below an area of the material stack to suspend a portion of the material stack over a portion of the substrate, using a portion of the substrate to support the suspended material stack; and

using at least one of the first and second materials to induce a strain in the active material.

25 86. The method of claim **85**, wherein at least part of the material stack is formed prior to the removal of a portion of the substrate and suspension of a portion of the material stack over a portion of the substrate.

30 87. The method of claim **85**, wherein at least part of the material stack is formed after the removal of a portion of the substrate.

88. The method of claim **85**, wherein at least one of the first and second materials is configured and arranged to induce a strain in the active material.

89. The method of claim **85**, wherein at least one of the steps of forming a first material and forming a second material includes
5 selecting at least one of an electronic characteristic and optoelectronic characteristic for the active material,
selecting a configuration and arrangement of a material to induce a strain in the active material in order to set at least one of an electronic characteristic and optoelectronic characteristic of the active material to the selected electronic characteristic or optoelectronic characteristic, and
10 forming the material having the selected configuration and arrangement.
90. The method of claim **85**, wherein removing a portion of the substrate below an area of the material stack includes using an etch process starting
15 at the topside of the substrate.
91. The method of claim **85**, wherein removing a portion of the substrate below an area of the material stack includes using an etch process starting at the backside of the substrate.
20
92. The method of claim **85**, wherein using at least one of the first and second materials to induce a strain in the active material includes
forming the second material connected to a surface of the active material after removing a portion of the substrate to suspend a portion of
25 the first material and active material, and
using the second material to induce a strain in the suspended portion of the active material.
93. The method of claim **85**, wherein using at least one of the first and second materials to induce a strain in the active material includes
30 removing a portion of the substrate to suspend a portion of the material stack, after forming the material stack, and
using the second material to induce a strain in the suspended portion of the active material.

- 5 94. The method of claim **85**, further including removing the material stack from the substrate, after a strain has been induced therein, and installing the material stack in at least one of an electronic device and optoelectronic device.
95. The method of claim **85**, further including refilling an area of the removed portion of the substrate with another material.
- 10 96. A method of manufacturing a semiconductor device, the method comprising:
forming a first material on a substrate;
forming a material stack by
forming an active material on the first material, and
15 forming a second material connected to a surface of the active material;
removing a portion of the first material below an area of the material stack to suspend a portion of the material stack over a portion of the first material, using a portion of the first material to support the suspended
20 material stack; and
using at least one of the first and second materials to induce a strain in the active material.
- 25 97. The method of claim **96**, wherein at least part of the material stack is formed prior to the removal of a portion of the first material and suspension of a portion of the material stack over a portion of the first material.
98. The method of claim **96**, wherein at least part of the material stack is formed after the removal of a portion of the first material.
- 30 99. The method of claim **96**, wherein at least one of the first and second materials is configured and arranged to induce a strain in the active material.

100. The method of claim **96**, wherein at least one of the steps of forming a first material and forming a second material includes
- selecting at least one of an electronic characteristic and optoelectronic characteristic for the active material,
- selecting a configuration and arrangement of a material to induce a strain in the active material in order to set at least one of an electronic characteristic and optoelectronic characteristic of the active material to the selected electronic characteristic or optoelectronic characteristic, and
- forming the material having the selected configuration and arrangement.
101. The method of claim **96**, wherein removing a portion of the first material below an area of the material stack includes using an etch process starting at the topside of the first material.
102. The method of claim **96**, wherein using at least one of the first and second materials to induce a strain in the active material includes
- forming the second material connected to a surface of the active material after removing a portion of the first material to suspend a portion of the active material, and
- using the second material to induce a strain in the suspended portion of the active material.
103. The method of claim **96**, wherein using at least one of the first and second materials to induce a strain in the active material includes
- removing a portion of the first material to suspend a portion of the material stack, after forming the material stack, and
- using the second material to induce a strain in the suspended portion of the active material.
104. The method of claim **96**, further including removing the material stack from the substrate, after a strain has been induced therein, and installing the material stack in at least one of an electronic device and optoelectronic device.

105. The method of claim **96**, further including refilling an area of the removed portion of the first material with another material.

5 106. A method of manufacturing a semiconductor device, the method comprising:

forming a first material on a substrate;

forming a material stack by

forming an active material on the first material, and

10 forming a second material connected to a surface of the active material;

removing a portion of the first material and substrate below an area of the material stack to suspend a portion of the material stack over a portion of the first material and substrate, using a portion of the first material and substrate to support the suspended material stack; and

15 using at least one of the first and second materials to induce a strain in the active material.

20 107. The method of claim **106**, wherein at least part of the material stack is formed prior to the removal of a portion of the first material and substrate and suspension of a portion of the material stack over a portion of the first material and substrate.

25 108. The method of claim **106**, wherein at least part of the material stack is formed after the removal of a portion of the first material and substrate.

109. The method of claim **106**, wherein at least one of the first and second materials is configured and arranged to induce a strain in the active material.

30 110. The method of claim **106**, wherein at least one of the steps of forming a first material and forming a second material includes selecting at least one of an electronic characteristic and optoelectronic characteristic for the active material,

selecting a configuration and arrangement of a material to induce a strain in the active material in order to set at least one of an electronic characteristic and optoelectronic characteristic of the active material to the selected electronic characteristic or optoelectronic characteristic, and

5 forming the material having the selected configuration and arrangement.

111. The method of claim **106**, wherein removing a portion of the first material and substrate below an area of the material stack includes using an etch process starting at the topside of the first material.

112. The method of claim **106**, wherein removing a portion of the first material and substrate below an area of the material stack includes using an etch process starting at the backside of the substrate.

113. The method of claim **106**, wherein using at least one of the first and second materials to induce a strain in the active material includes forming the second material connected to a surface of the active material after removing a portion of the first material and substrate to suspend a portion of the active material, and using the second material to induce a strain in the suspended portion of the active material.

114. The method of claim **106**, wherein using at least one of the first and second materials to induce a strain in the active material includes removing a portion of the first material and substrate to suspend a portion of the material stack, after forming the material stack, and using the second material to induce a strain in the suspended portion of the active material.

115. The method of claim **106**, further including removing the material stack from the substrate, after a strain has been induced therein, and installing the material stack in at least one of an electronic device and optoelectronic device.

116. The method of claim **106**, further including refilling an area of the removed portion of the first material and substrate with another material.

5 117. A method of manufacturing a semiconductor device, the method comprising:

forming a material stack by

forming an active material on a substrate, and

forming a strain-inducing material connected to a surface of the

10 active material; and

using a support structure to suspend a portion of the active material over a portion of the substrate.

118. The method of claim **117**, wherein at least part of the material stack is
15 formed prior to the suspension of a portion of the material stack over a portion of the substrate.

119. The method of claim **117**, wherein at least part of the material stack is
20 formed after the suspension of a portion of the material stack over a portion of the substrate.

120. The method of claim **117**, wherein at least one of the steps of forming a strain-inducing material includes

25 selecting at least one of an electronic characteristic and optoelectronic characteristic for the active material,

selecting a configuration and arrangement of the material to induce a strain in the active material in order to set at least one of an electronic characteristic and optoelectronic characteristic of the active material to the selected electronic characteristic or optoelectronic characteristic, and

30 forming the material having the selected configuration and arrangement.

121. The method of claim **117**, wherein using a support structure to suspend a portion of the active material over a portion of the substrate includes

connecting the active material to a support structure and using the support structure to hold the active material in a suspended state above a portion of the substrate.

- 5 122. The method of claim **117**, further including removing the active material from the support structure, after a strain has been induced therein, and installing the active material in at least one of an electronic device and optoelectronic device.
- 10 123. A method of manufacturing a semiconductor device, the method comprising:
 forming a material stack by
 forming a strained active material on a substrate, and
 forming a material connected to a surface of the strained active
15 material; and
 forming a support structure to suspend a portion of the strained active material over a portion of the substrate.
- 20 124. The method of claim **123**, wherein at least part of the strained material stack is formed prior to the suspension of a portion of the strained material stack over a portion of the substrate.
- 25 125. The method of claim **123**, wherein at least part of the strained material stack is formed after the suspension of a portion of the strained material stack over a portion of the substrate.
- 30 126. The method of claim **123**, wherein at least one of the steps of forming a material includes
 selecting a configuration and arrangement of the material to mitigate relaxation of the strain induced in the active material, and
 forming the material having the selected configuration and arrangement.
127. The method of claim **123**, wherein using a support structure to suspend a

portion of the strained active material over a portion of the substrate includes connecting the strained active material to a support structure and using the support structure to hold the strained active material in a suspended strained state above a portion of the substrate.

5

128. The method of claim **123**, further including removing the strained active material from the support structure and installing it in at least one of an electronic device and optoelectronic device.

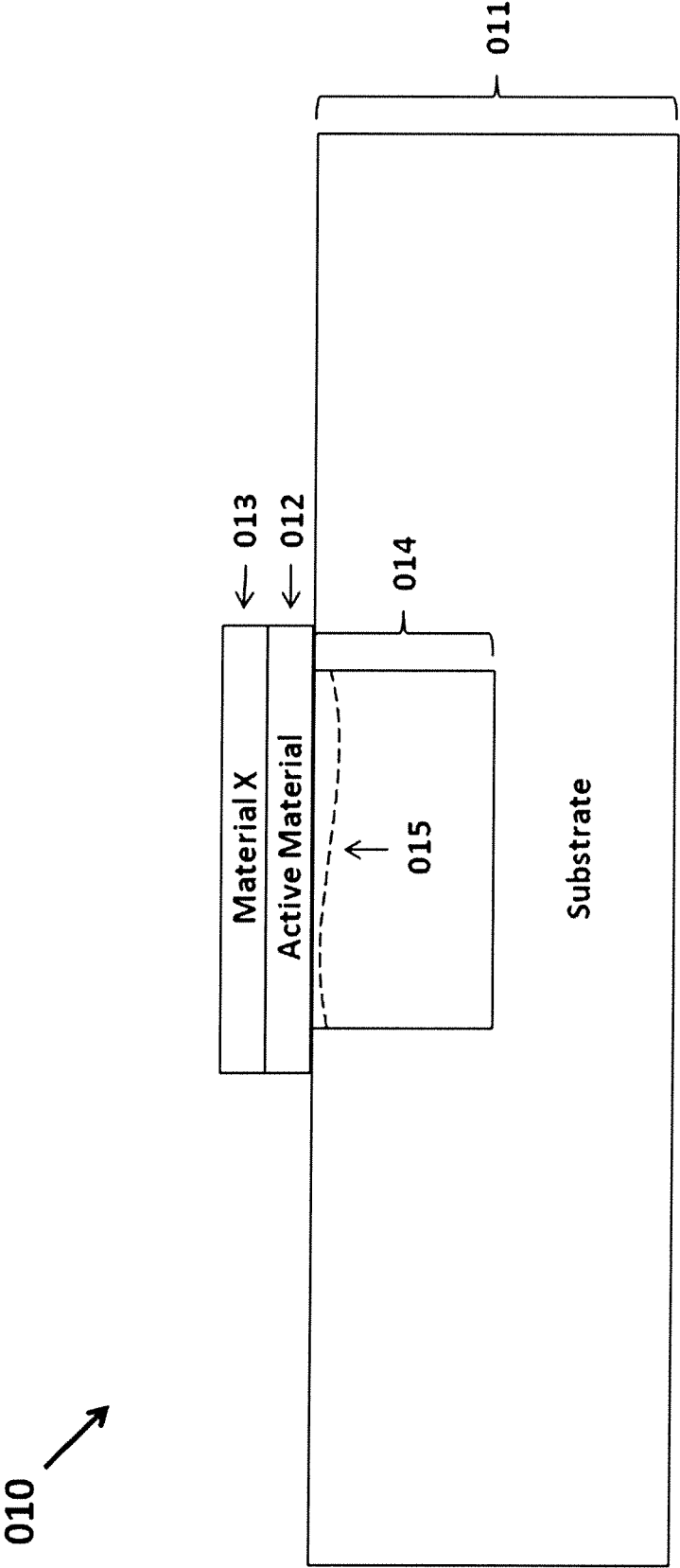


FIG. 1

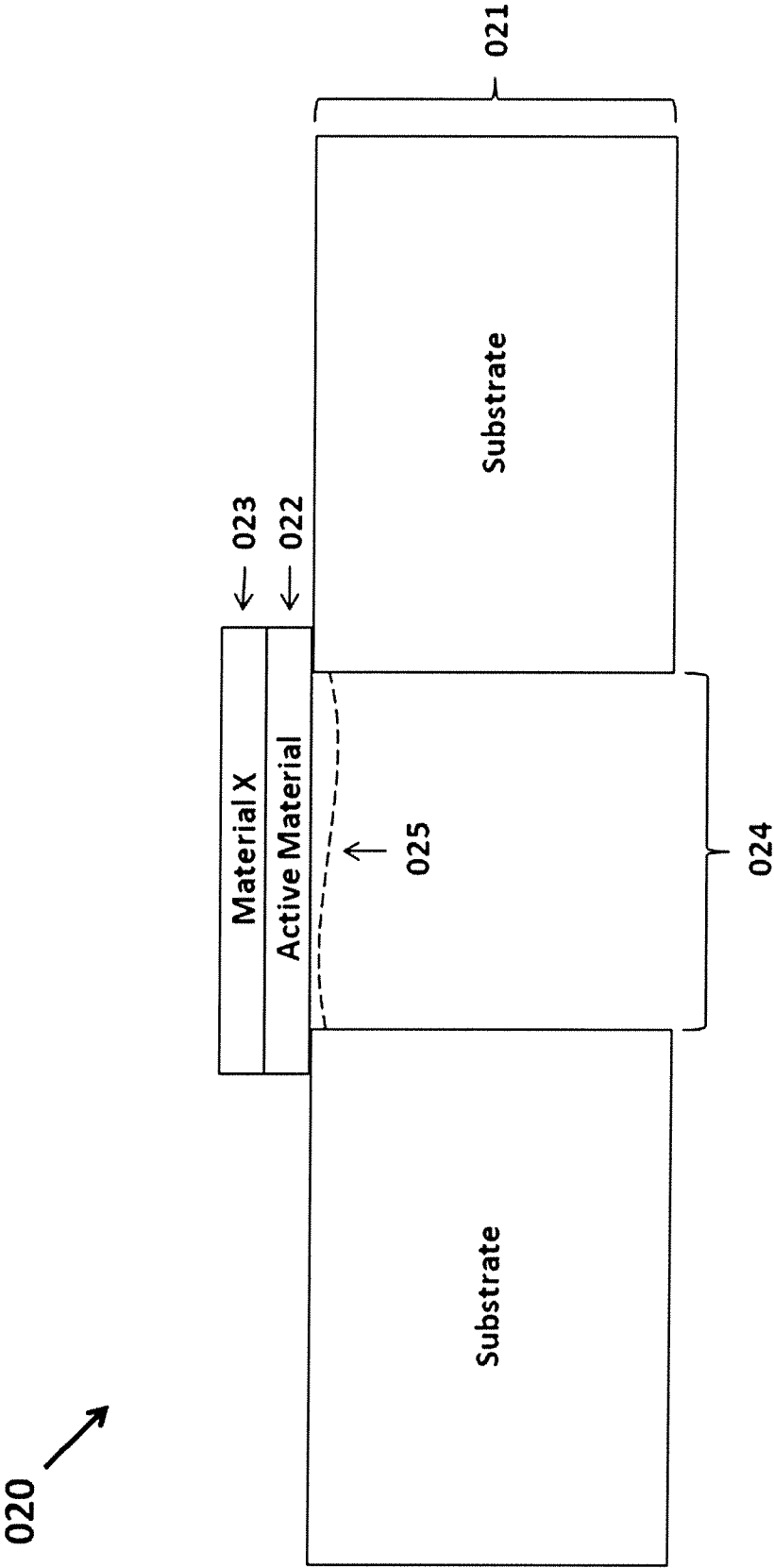


FIG. 2

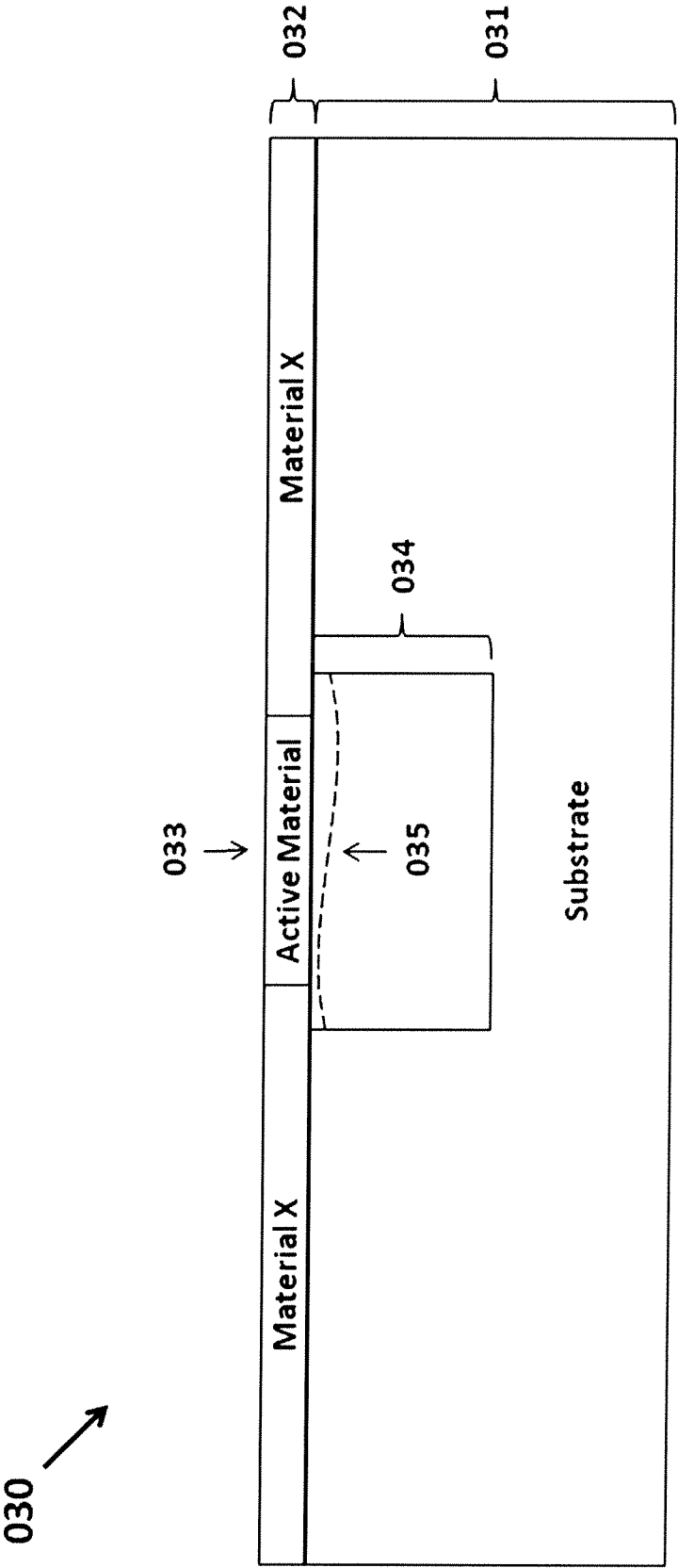


FIG. 3

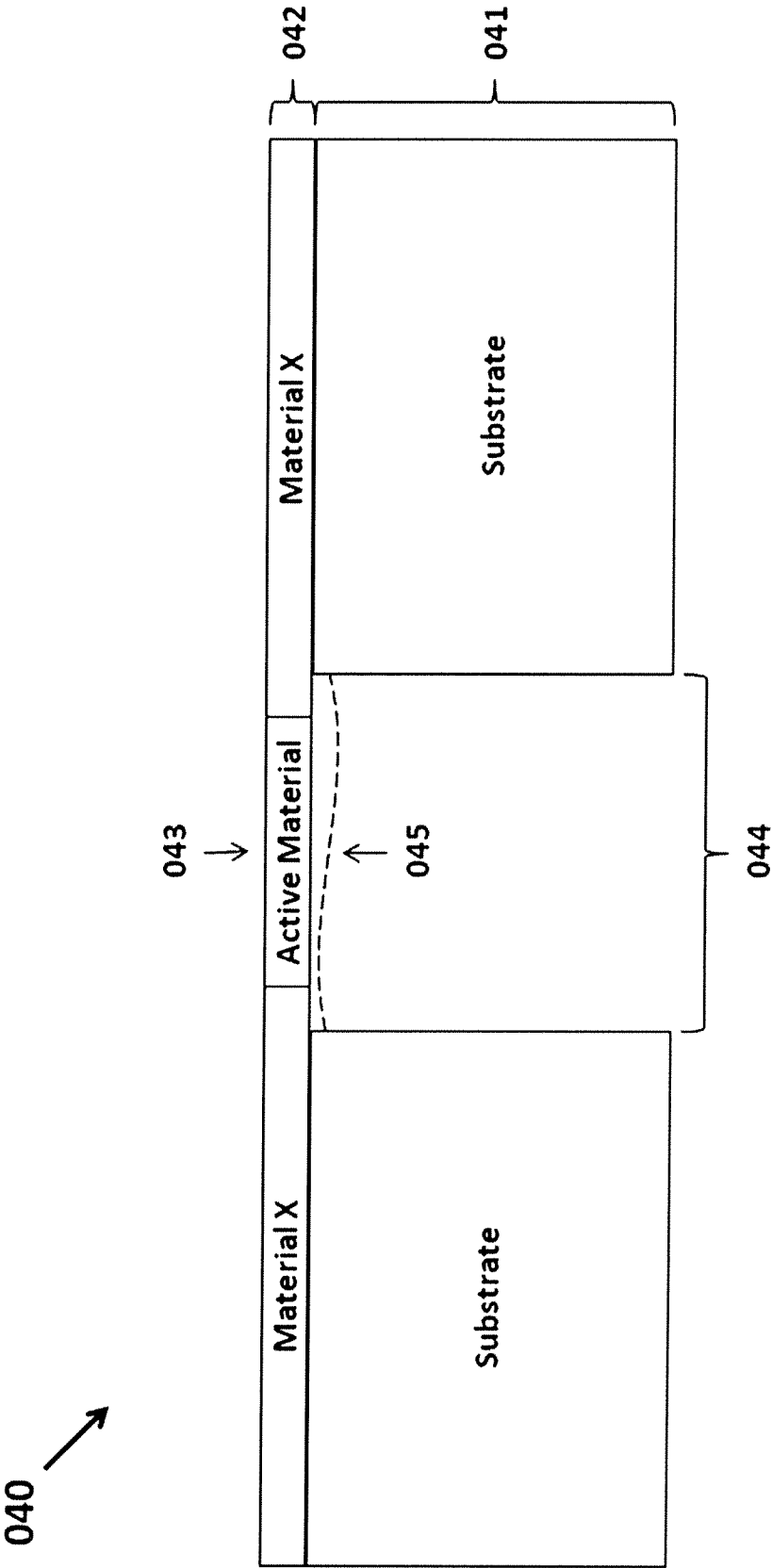


FIG. 4

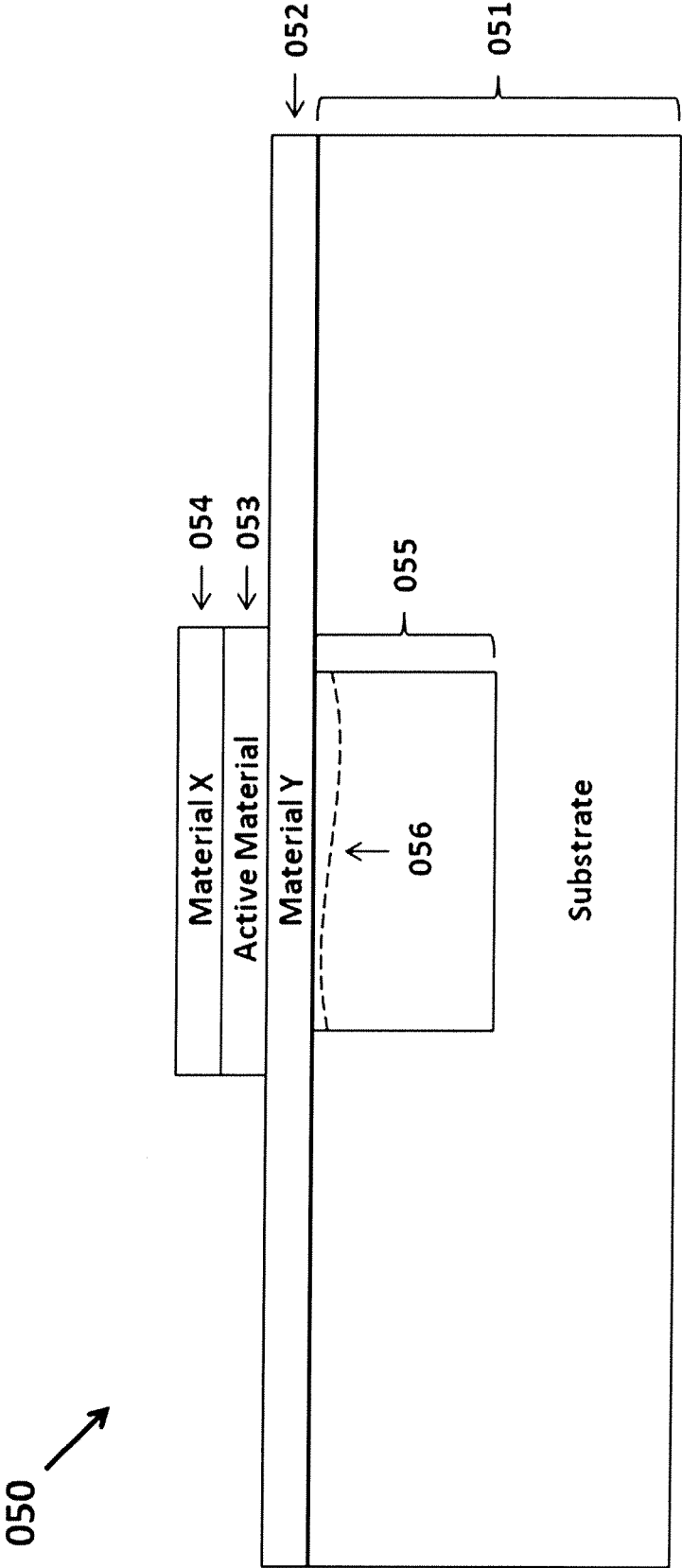


FIG. 5

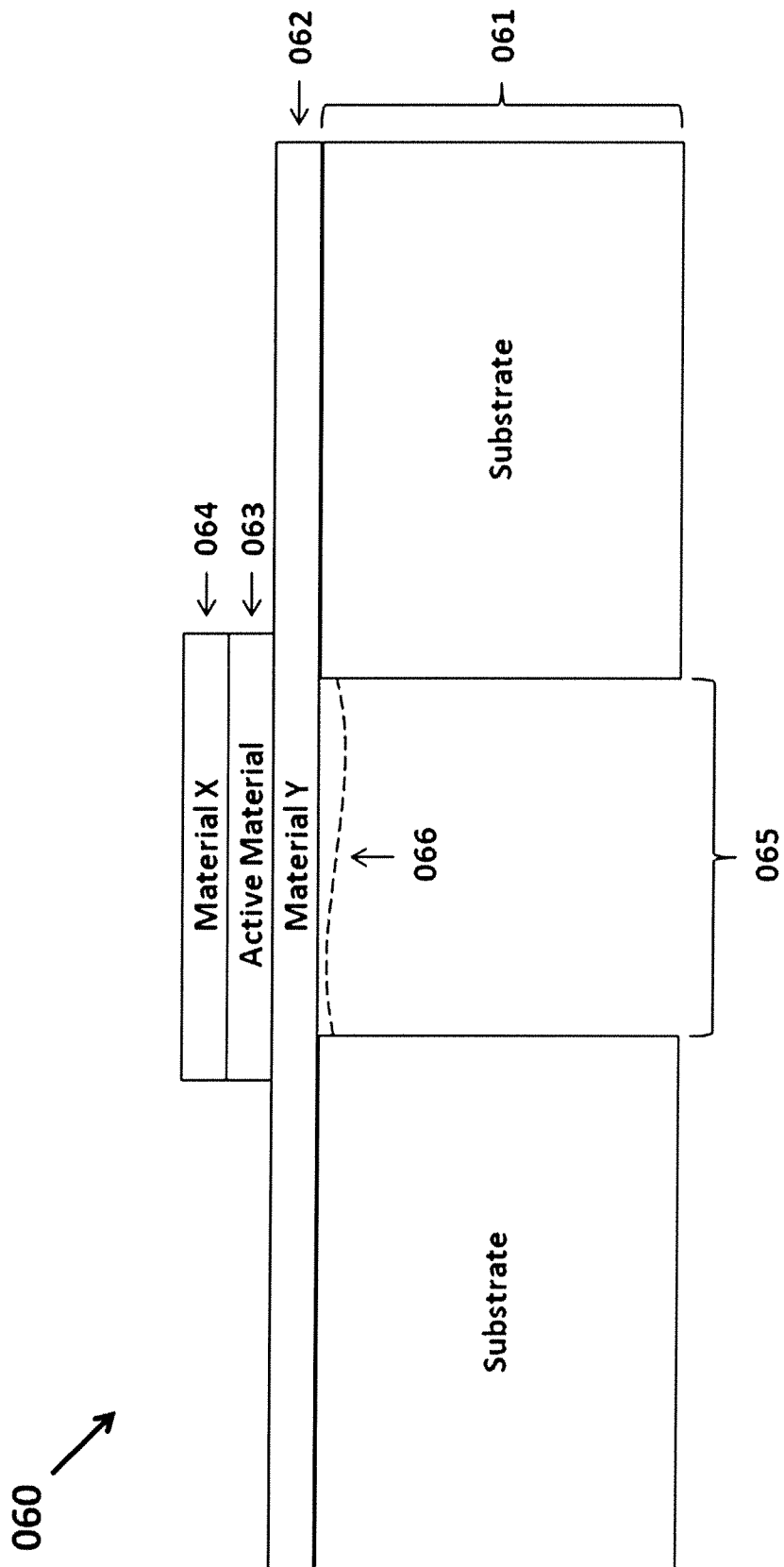


FIG. 6

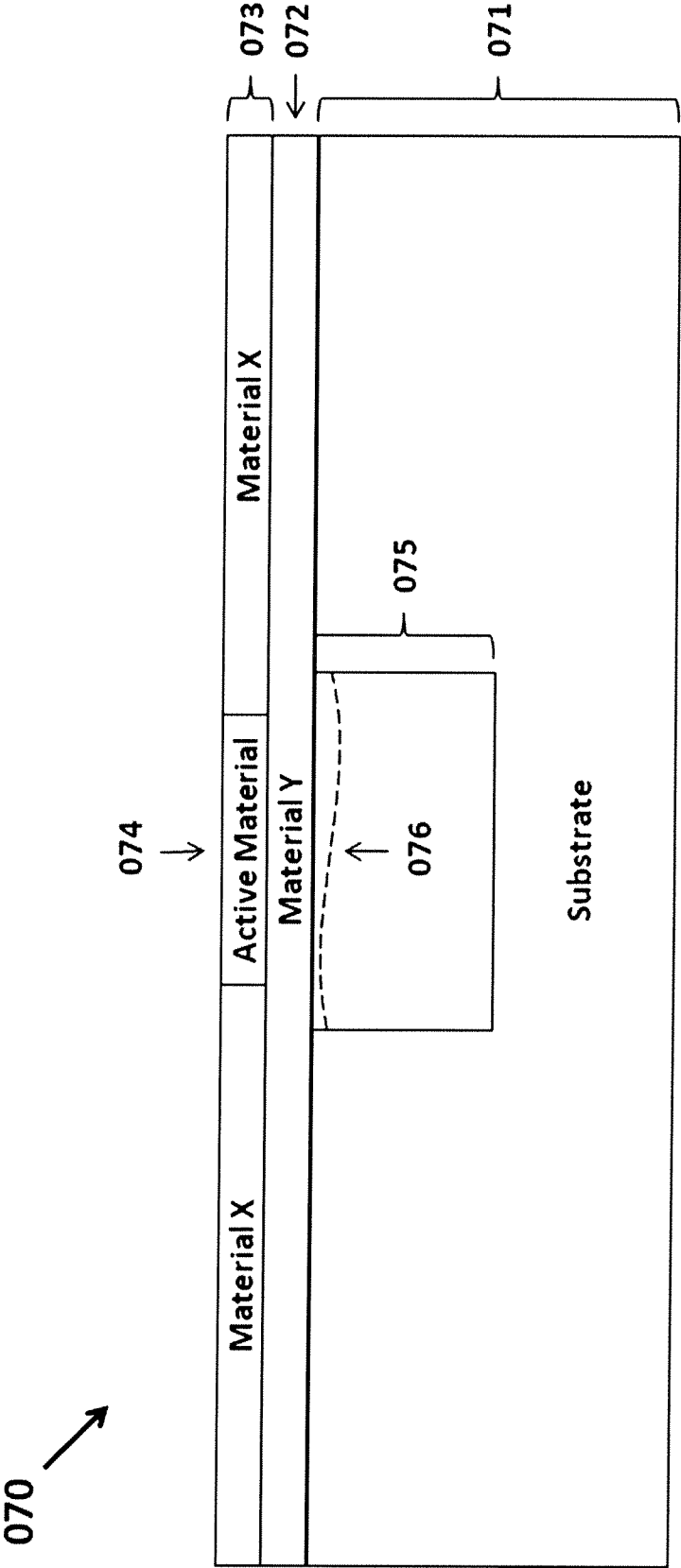


FIG. 7

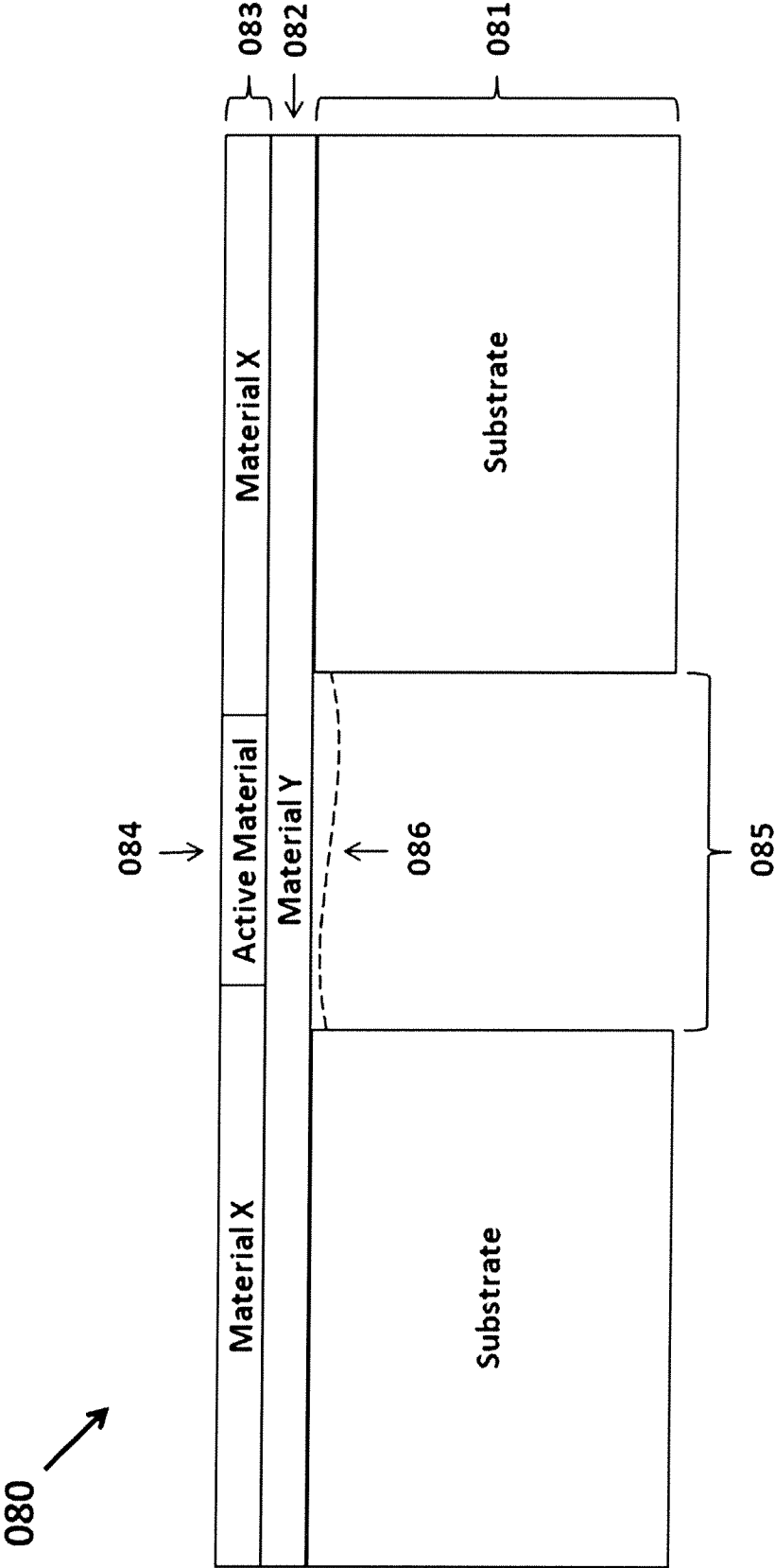


FIG. 8

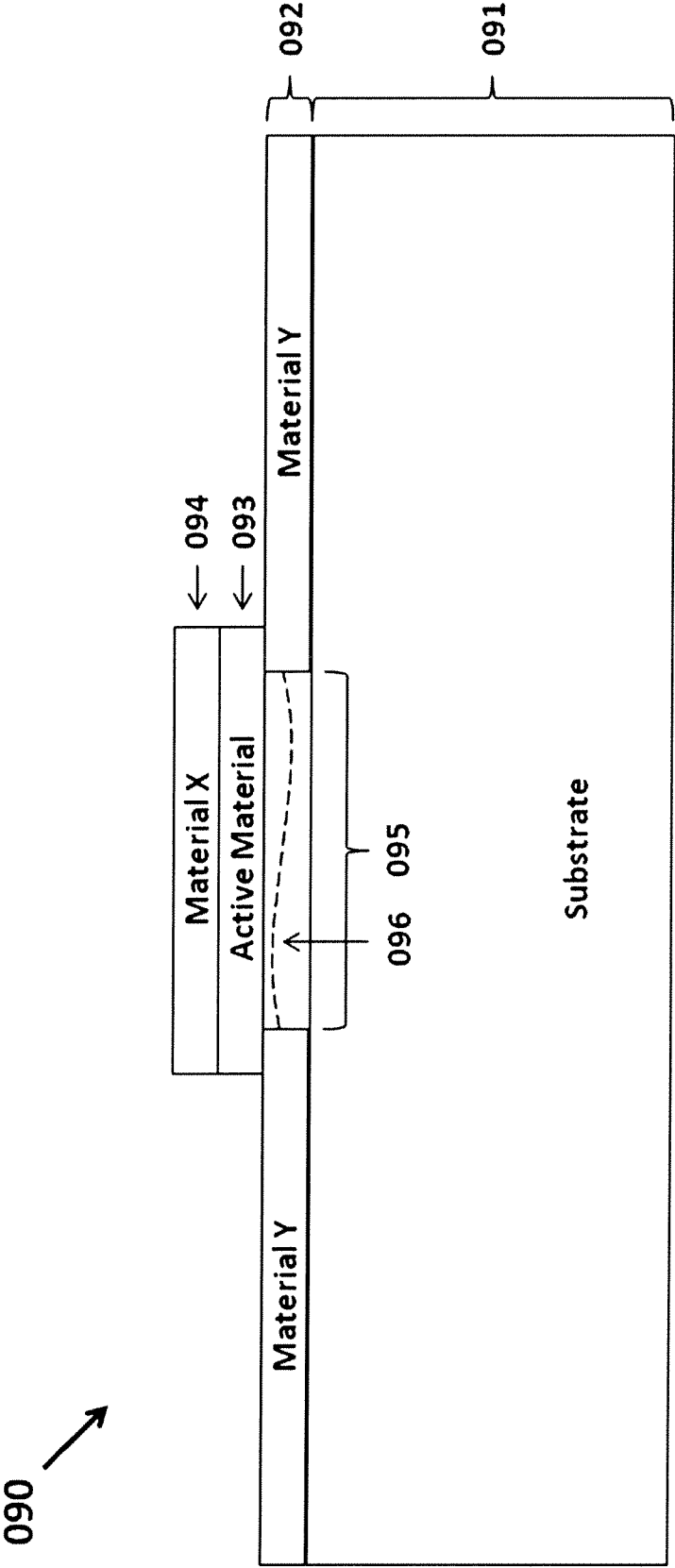


FIG. 9

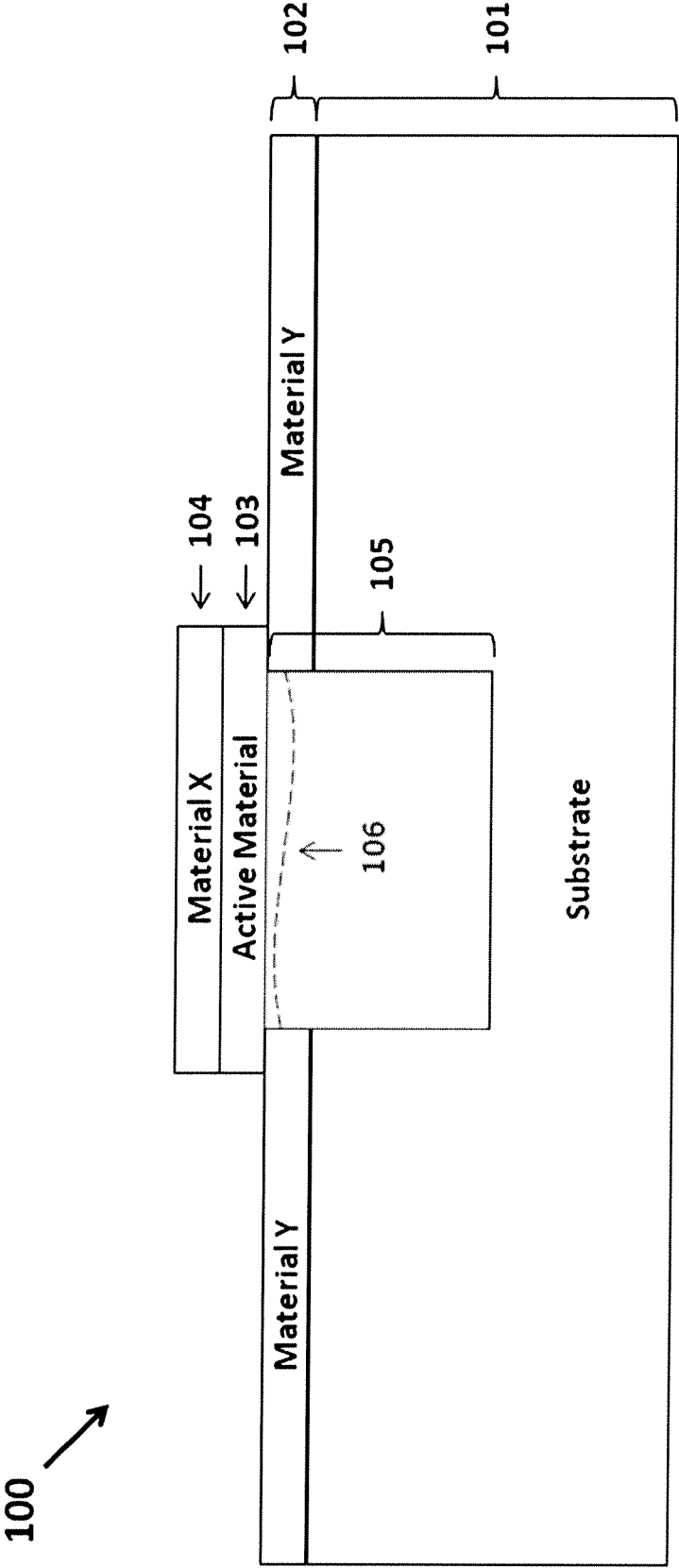


FIG. 10

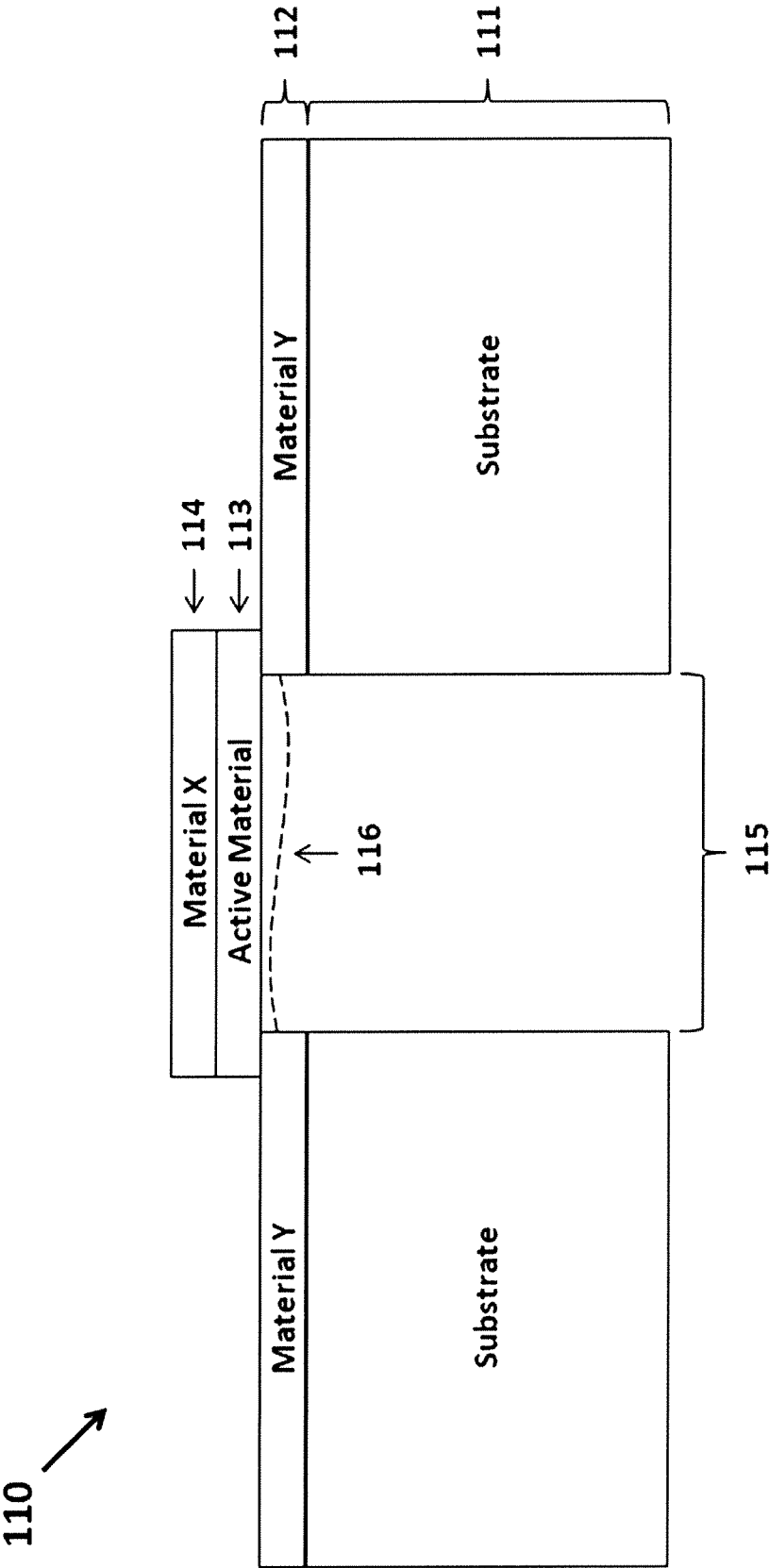


FIG. 11

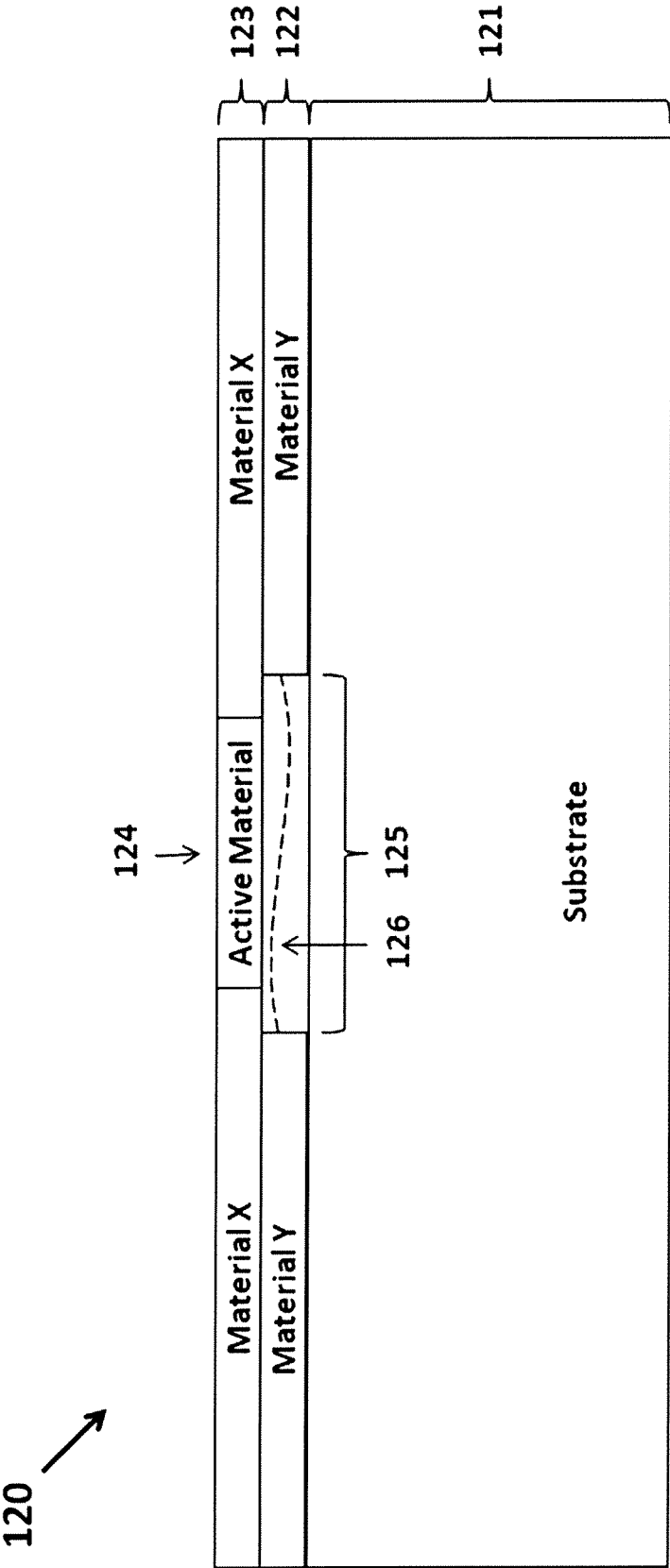


FIG. 12

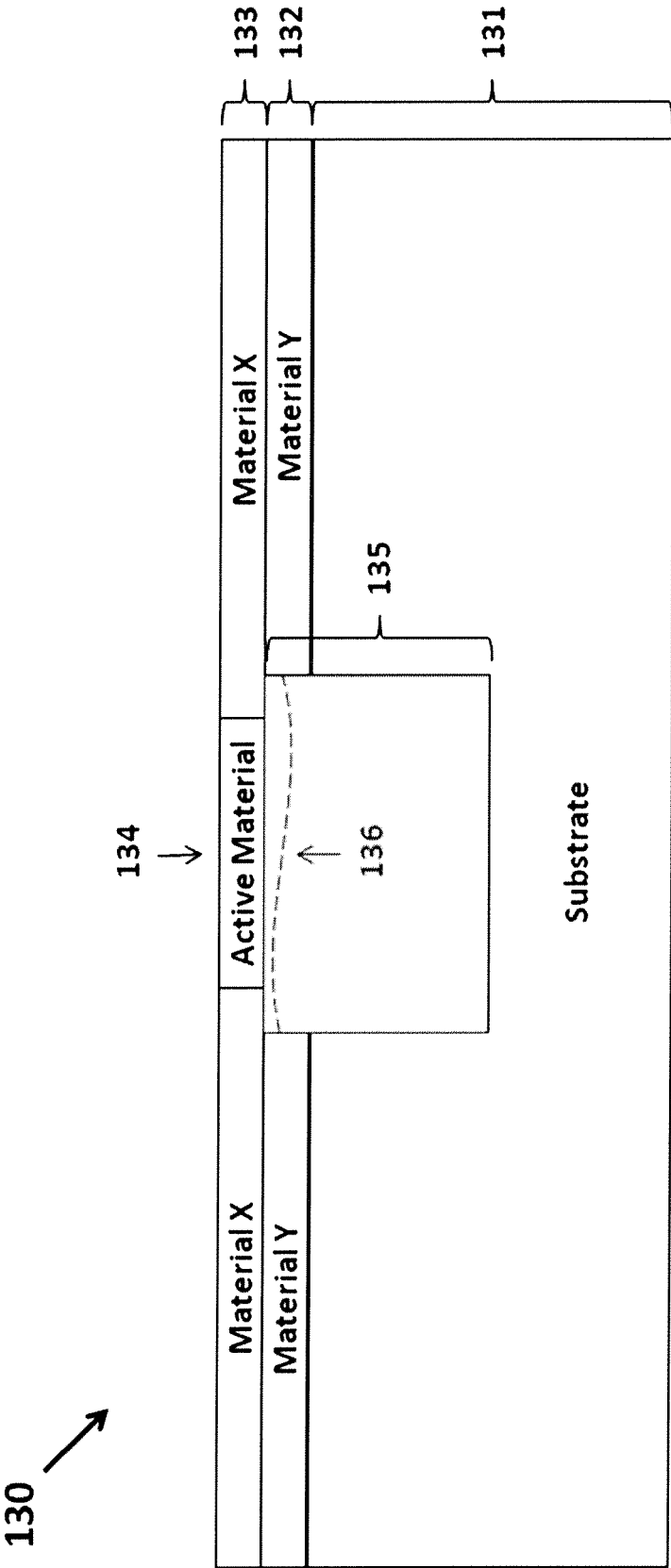


FIG. 13

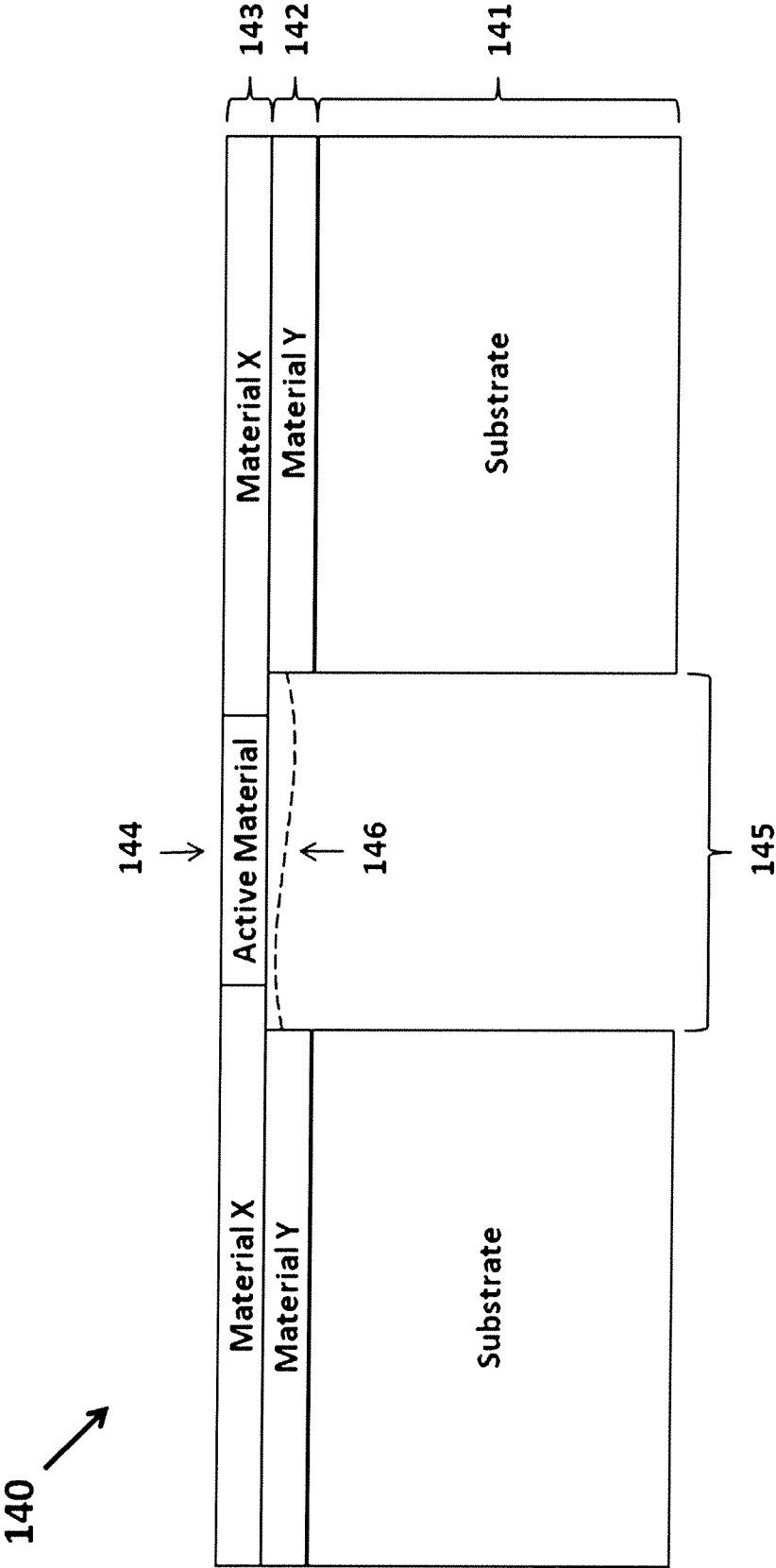


FIG. 14

INTERNATIONAL SEARCH REPORT

International application No.

PCT/US 10/24302

A. CLASSIFICATION OF SUBJECT MATTER

IPC(8) - H01L 21/28, 21/762 (2010.01)

USPC - 257/369; 257/649

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

IPC- H01L 21/28, 21/762 (2010.01);

USPC- 257/369; 257/649

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

USPC- 257/E21.19, 257/E21.546, 257/E27.062, 438/221;

Patents and NPL

Electronic data base consulted during the international search (name of data base and, where practicable, search terms used)

PubWest (US Pat, PgPub, EPO, JPO: class, keyword), DialogClassic (Derwent, EPO, JPO, USPTO, WIPO: keyword), GoogleScholar; search terms: semiconductor, suspend, cavity, strain, relax, material

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category*	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
Y	US 2004/0232504 A1 (LAL et al.) 25 November 2004 (25.11.2004), Figs. 6, 11, and 13; para [0033]-[0036]	1-128
Y	US 2004/0253792 A1 (COHEN et al.) 16 December 2004 (16.12.2004), para [0008], [0009], [0028], [0046], [0080], [0085]-[0087], [0113]	1-128
Y, P	US 2009/0243003 A1 (RENNÄ et al.) 01 October 2009 (01.10.2009), entire document	1-128
Y, P	US 2009/0155964 A1 (CHANG et al.) 18 June 2009 (18.06.2009), entire document	1-128
Y, P	US 2009/0045394 A1 (SMEETON et al.) 19 February 2009 (19.02.2009), entire document	1-128

☐ Further documents are listed in the continuation of Box C.

* Special categories of cited documents:

"A" document defining the general state of the art which is not considered to be of particular relevance

"E" earlier application or patent but published on or after the international filing date

"L" document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified)

"O" document referring to an oral disclosure, use, exhibition or other means

"P" document published prior to the international filing date but later than the priority date claimed

"T" later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention

"X" document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone

"Y" document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art

"&" document member of the same patent family

Date of the actual completion of the international search

24 March 2010 (24.03.2010)

Date of mailing of the international search report

12 APR 2010

Name and mailing address of the ISA/US

Mail Stop PCT, Attn: ISA/US, Commissioner for Patents
P.O. Box 1450, Alexandria, Virginia 22313-1450

Facsimile No. 571-273-3201

Authorized officer:

Lee W. Young

PCT Helpdesk: 571-272-4300

PCT OSP: 571-272-7774